

Lecture

14

ECE M216A

Energy-Delay Optimization

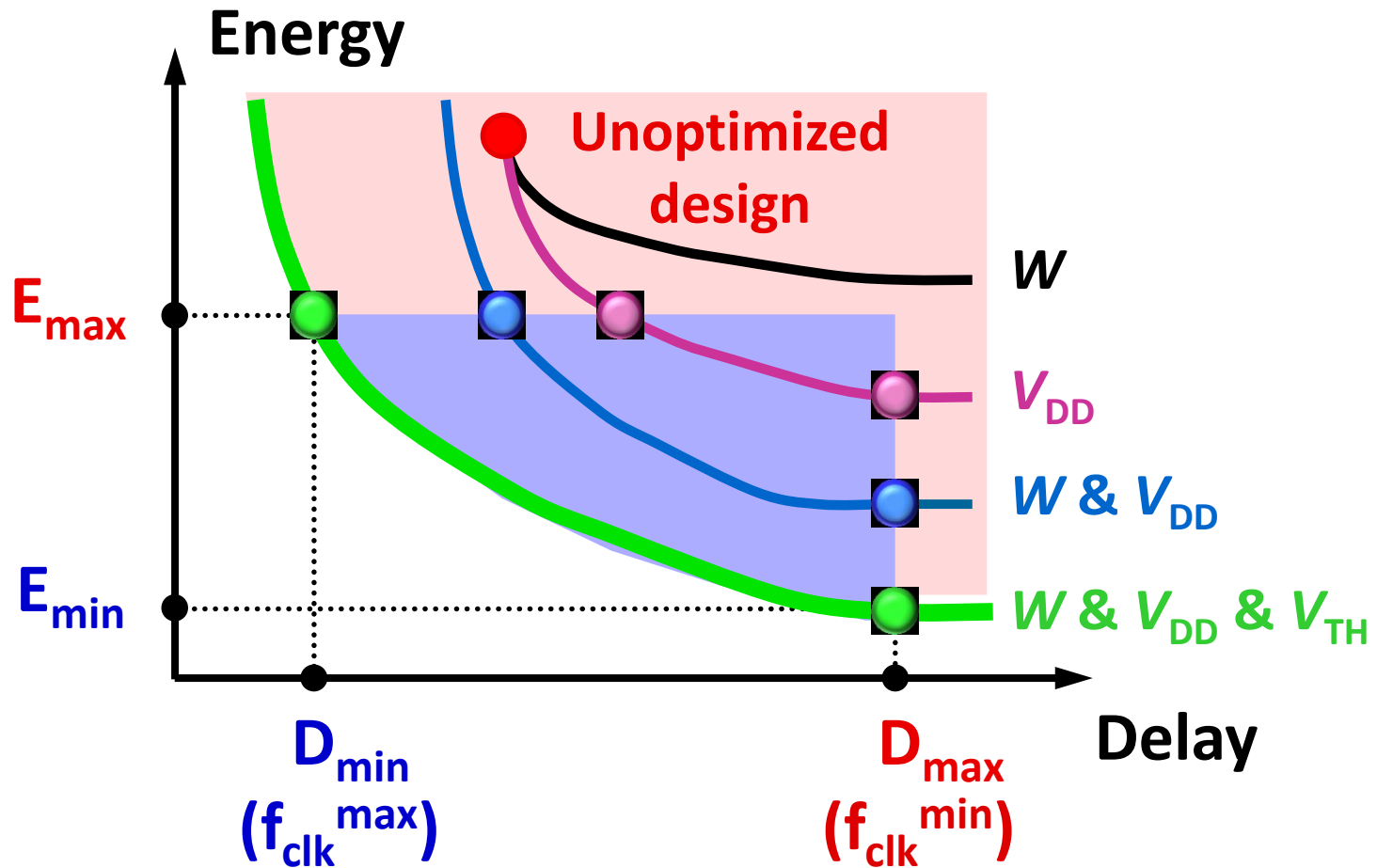
Prof. Dejan Marković

ee216a@gmail.com

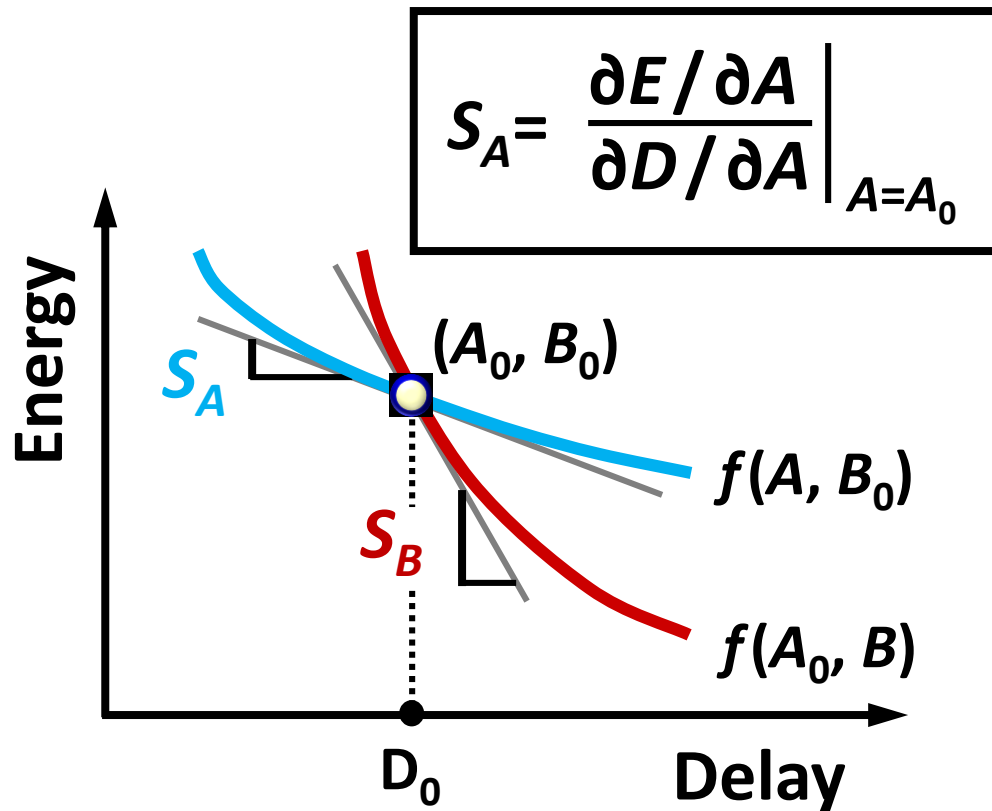
Some Common Questions

- Is sizing better than V_{DD} for energy reduction?
- Optimal values of gate size and V_{DD} ?
- Increase or decrease V_{DD} for energy reduction?
- Optimal ratio of leakage / switching for min E ?
- Optimal circuit topology?
- How many levels of parallelism?
- Etc.

Energy Minimization Problem



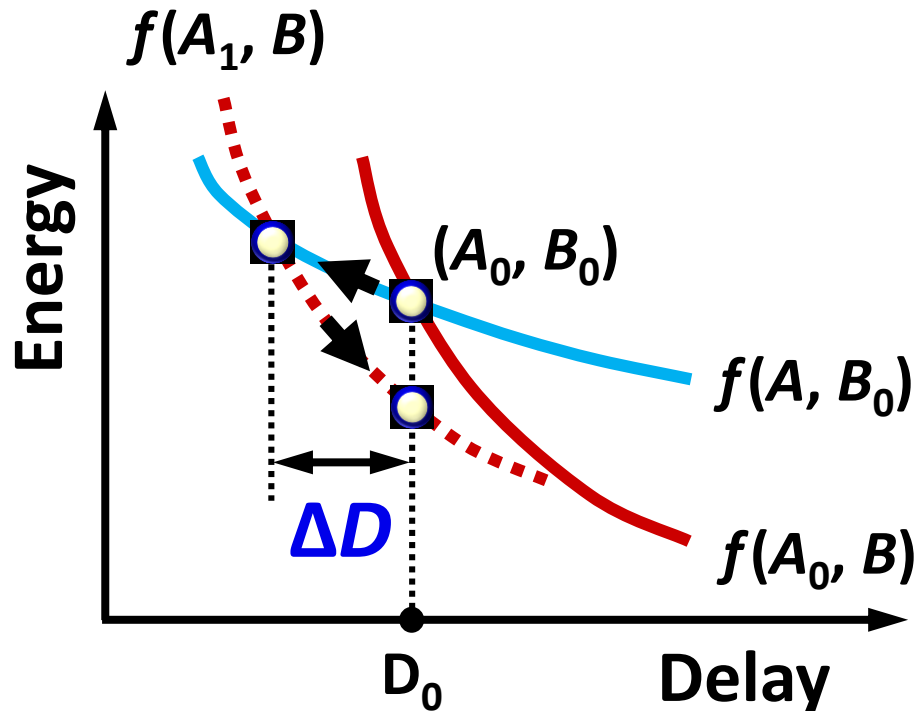
Energy-Delay Sensitivity



Slope of E-D curve around a design point (e.g. (A_0, B_0))

Solution: Equal Sensitivities

$$\Delta E = S_A \cdot (-\Delta D) + S_B \cdot \Delta D$$



A fixed point is reached when all sensitivities are equal

Circuit Optimization

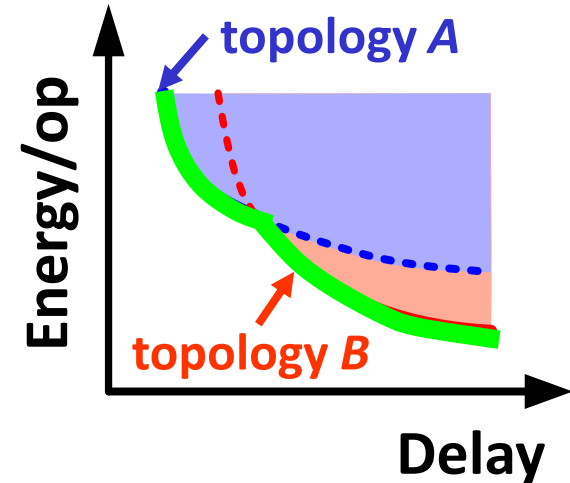
$$\begin{array}{ll} \text{minimize} & \text{Energy}(V_{dd}, V_{th}, W) \\ \text{subject to} & \text{Delay}(V_{dd}, V_{th}, W) \leq D_{con} \end{array}$$

Constraints

$$V_{dd}^{min} < V_{dd} < V_{dd}^{max}$$

$$V_{th}^{min} < V_{th} < V_{th}^{max}$$

$$W^{min} < W$$



- **Reference design**

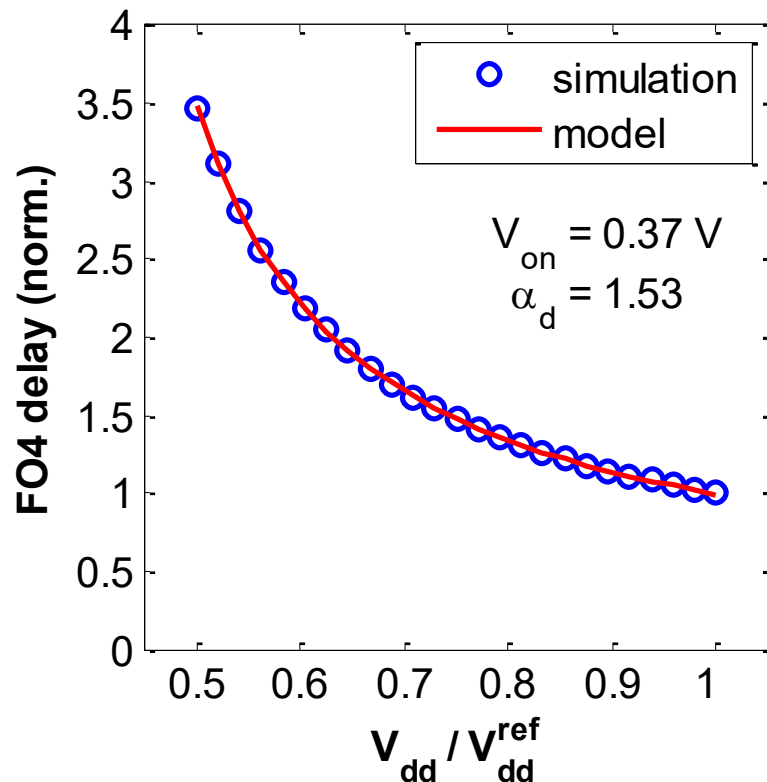
– D_{min} sizing @ V_{DD}^{max} ,
 V_{TH}^{ref}

Goal: find optimal
E-D tradeoff for a
logic function

Energy and Delay Models

Alpha-power based Delay Model

$$Delay = \frac{K_d \cdot V_{DD}}{(V_{DD} - V_{on} - \Delta V_T)^{\alpha_d}} \cdot \left(\frac{W_{out}}{W_{in}} + \frac{W_{par}}{W_{in}} \right)$$



Fitting parameters:

V_{on}, α_d, K_d

$$V_{DD}^{ref} = 1.2V$$

$$FO4 (V_{DD}^{ref}) = 25ps$$

(*) [Sutherland et al., Logical Effort, 1999]

Energy Model

- **Switching energy**

$$E_{sw} = \alpha_{0 \rightarrow 1} \cdot \left(C(W_{out}) + C(W_{par}) \right) \cdot V_{DD}^2$$

- **Leakage energy**

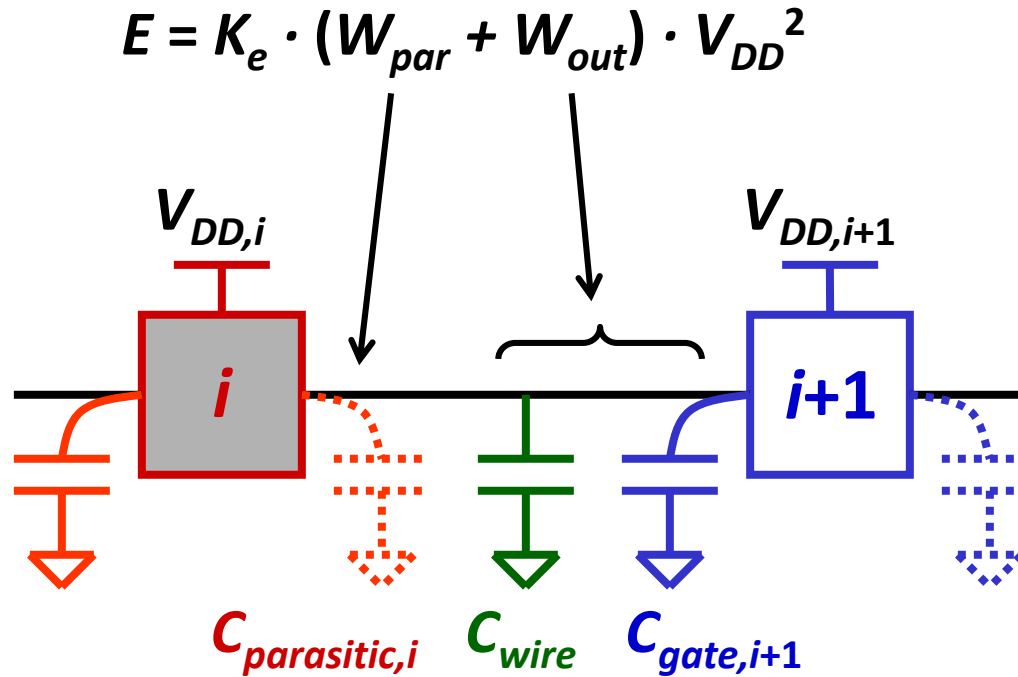
$$E_{lk} = \frac{W_{in}}{W_0} \cdot I_0(S_{in}) \cdot 10^{-\frac{V_T - \gamma_D V_{DD}}{S}} \cdot V_{DD} \cdot D$$

with:

D : the cycle time

$I_0(S_{in})$: normalized leakage current with inputs in state S_{in}

Adjusting Switching Energy of a Gate



Impact of opt variables

Sizing	W_i	Supply
	$W_{par,i}$	
	W_{out}	

$$ec_i = K_e \cdot W_i \cdot (V_{DD,i-1}^2 + p_{i,ref} \cdot V_{DD,i}^2)$$

(energy stored on the logic gate i)

Optimization

Optimization Setup

- **Reference/nominal circuit**

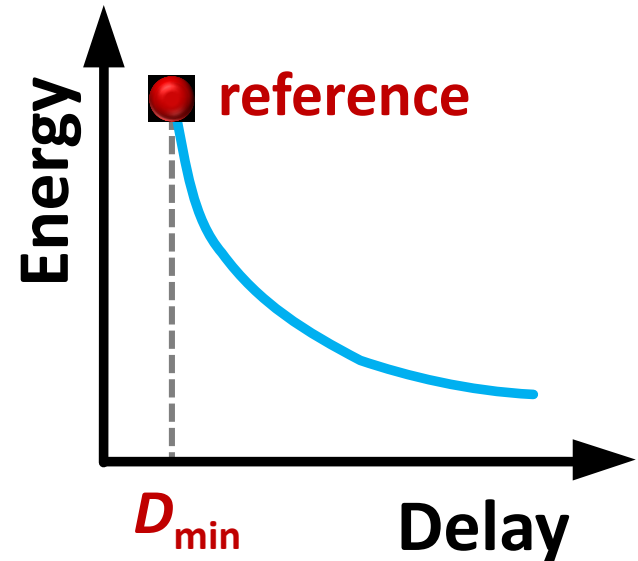
- Sized for $D_{\min}$ @ $V_{DD}^{\max}$, V_T^{ref}
- Known average activity

- **Define delay constraint**

- $D_{\text{con}} = D_{\min} (1 + d_{\text{inc}}/100)$

- **Minimize energy under delay constraint**

- Gate sizing (W), optional buffering
- V_{DD} and V_T scaling



Sensitivity to Sizing and Supply

- Gate sizing (W)

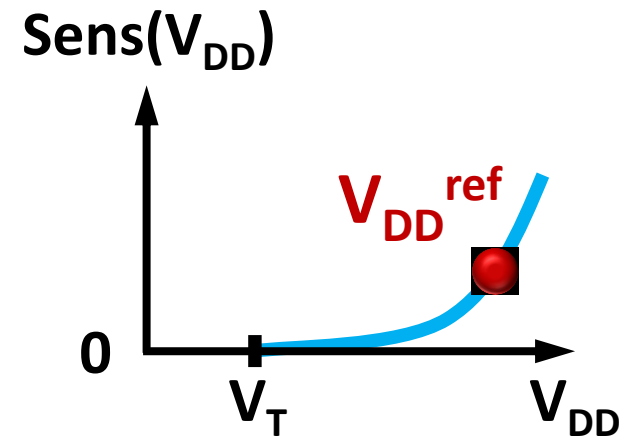
$$-\frac{\partial E_{Sw} / \partial W_i}{\partial D / \partial W_i} = \frac{ec_i}{\tau_{ref} \cdot (h_{eff,i} - h_{eff,i-1})}$$

$\propto$ for equal h_{eff}
(D_{min})

- Supply voltage (V_{DD})

$$-\frac{\partial E_{Sw} / \partial V_{DD}}{\partial D / \partial V_{DD}} = 2 \cdot \frac{E_{Sw}}{D} \cdot \frac{1 - x_v}{\alpha_d - 1 + x_v}$$

$$x_v = \frac{V_{on} + \Delta V_{TH}}{V_{DD}}$$



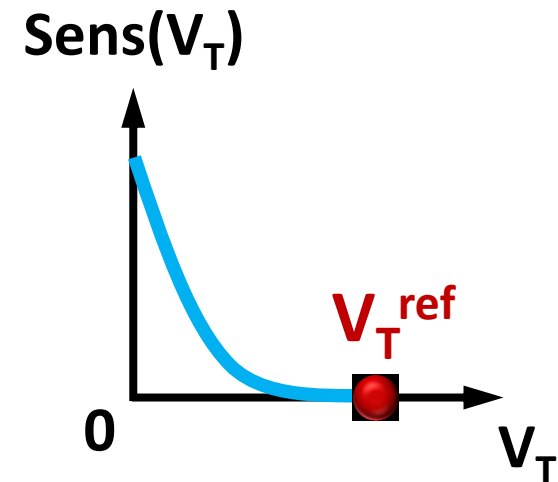
Sensitivity to Threshold Voltage

- Threshold voltage (V_T)

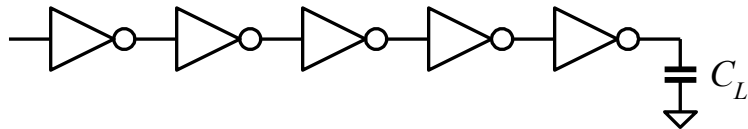
$$-\frac{\partial E / \partial(\Delta V_{TH})}{\partial D / \partial(\Delta V_{TH})} = P_{Lk} \cdot \left(\frac{V_{DD} - V_{on} - \Delta V_{TH}}{\alpha_d \cdot V_0} - 1 \right)$$

Low initial leakage

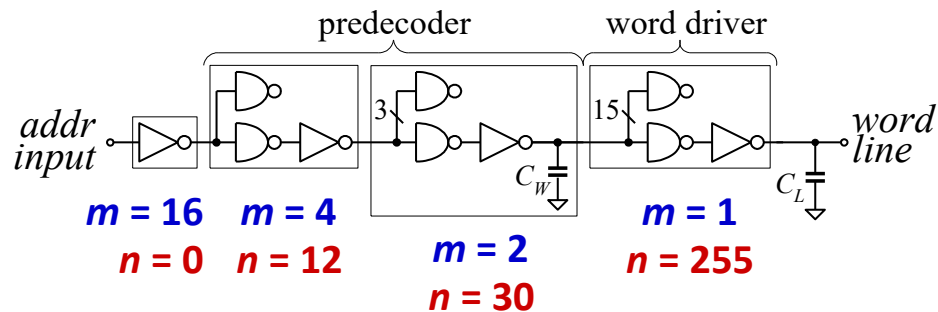
$\Rightarrow$ speedup comes for “free”



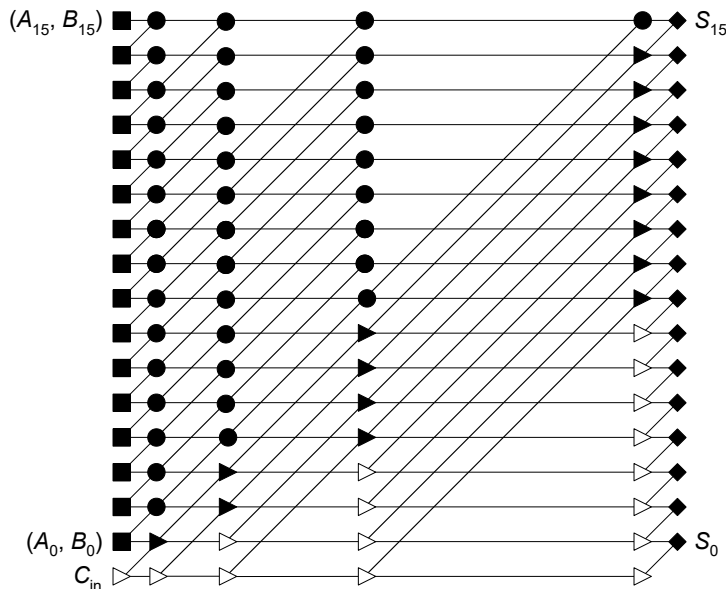
Circuit Optimization Examples



- Inverter chain



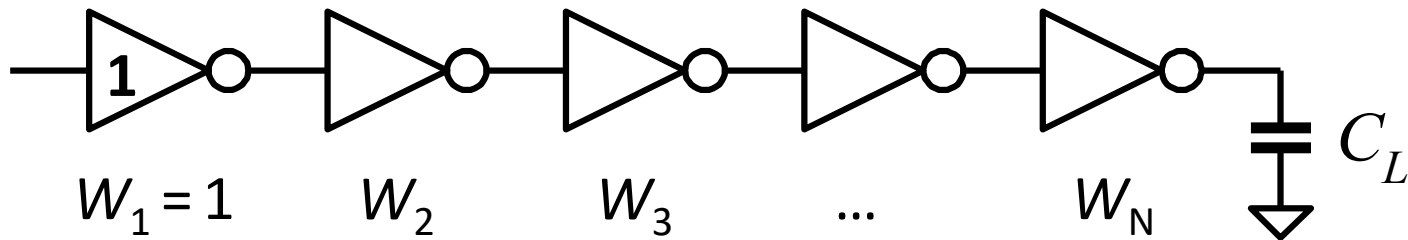
- Memory decoder
 - Branching
 - Inactive gates



- Tree adder
 - Long wires
 - Re-convergent paths
 - Multiple active outputs

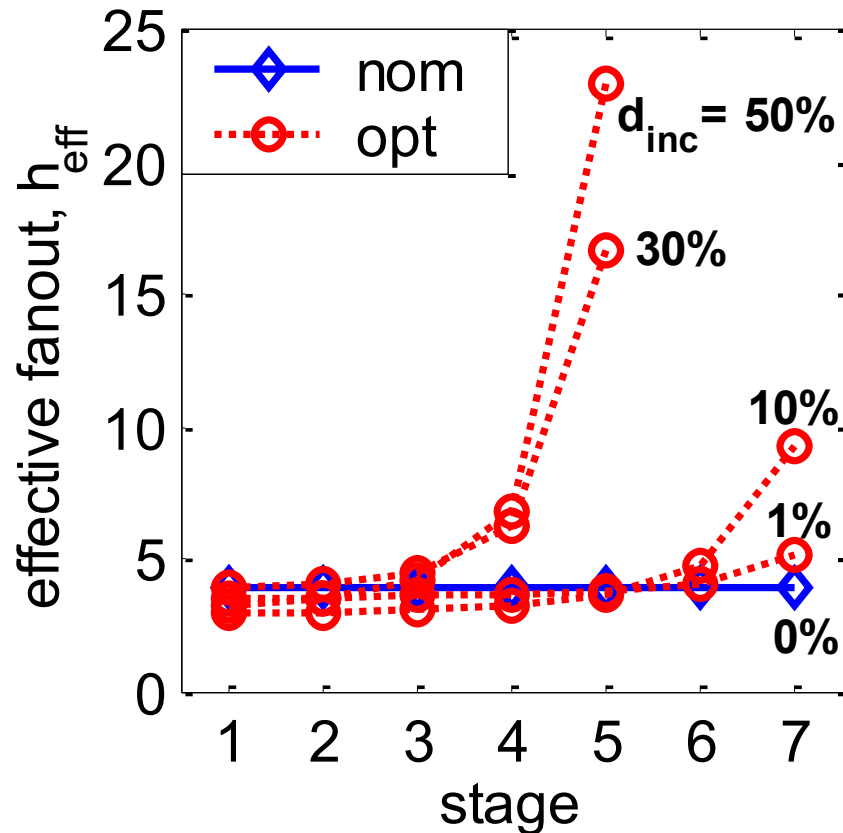
Example 14.1: Inverter Chain

- **Properties of inverter chain**
 - Single path topology
 - Energy increases geometrically from input to output



- **Goal**
 - Find optimal sizing $\mathbf{W} = [W_1, W_2, \dots, W_N]$, supply voltage and buffering strategy to minimize energy

Inverter Chain: Gate Sizing & Buffering



$$W_i^2 = \frac{W_{i-1} \cdot W_{i+1}}{1 + \mu \cdot W_{i-1}}$$

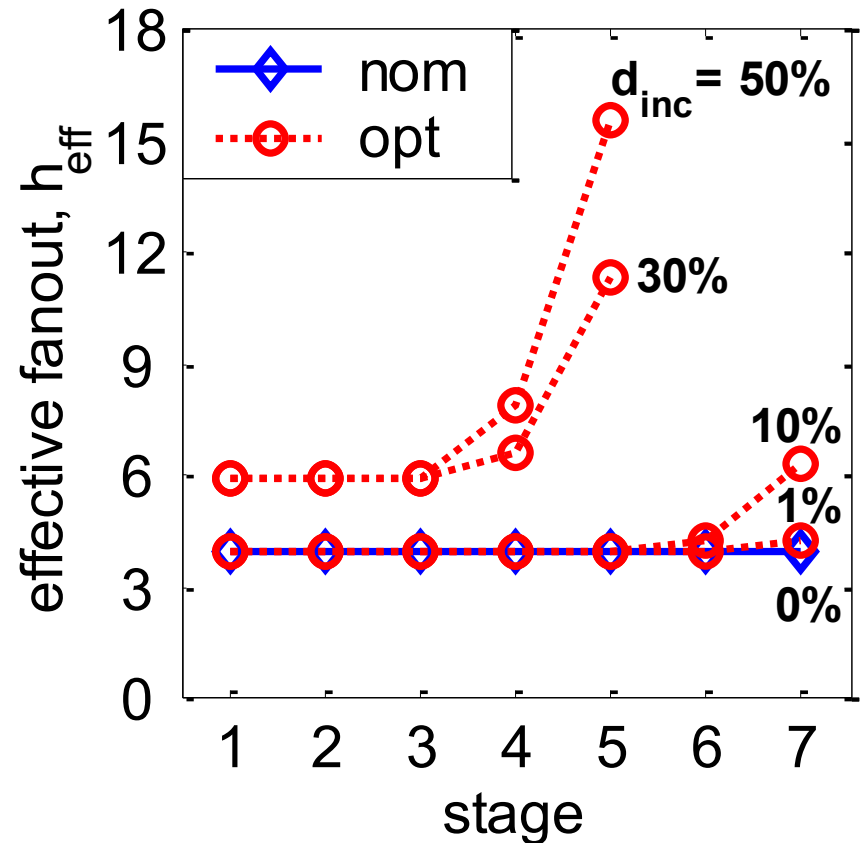
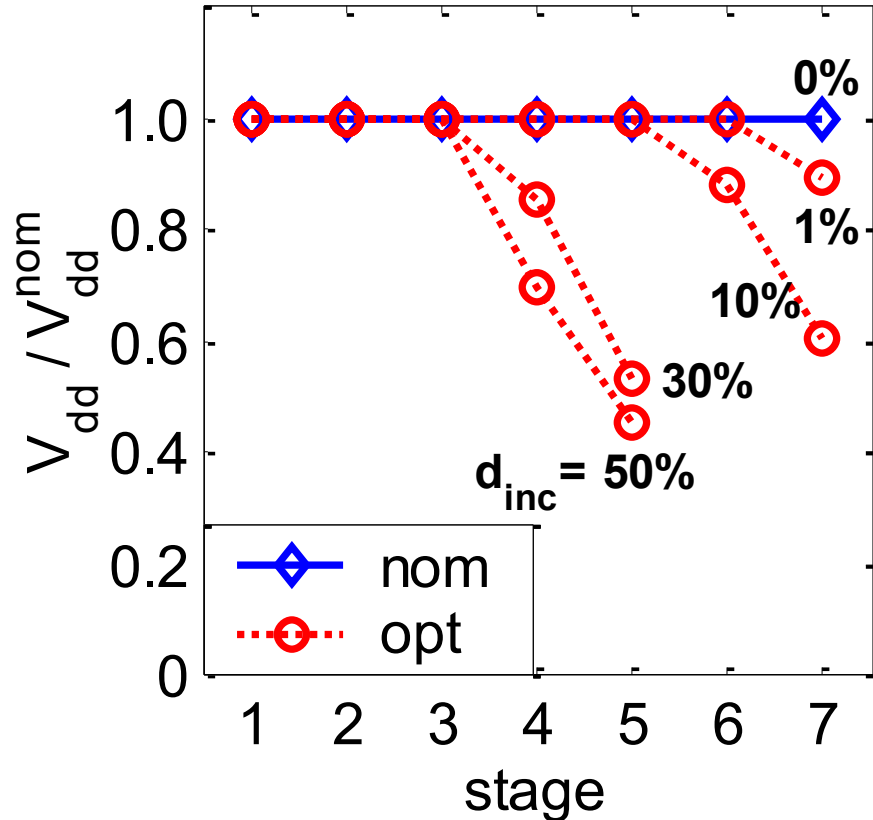
[Ma, Franzon, IEEE JSSC, 9/94]

$$\mu = -\frac{2 \cdot K_e \cdot V_{DD}^2}{\tau_{ref} \cdot S_W}$$

$$S_W \propto \frac{ec_i}{h_{eff,i} - h_{eff,i-1}}$$

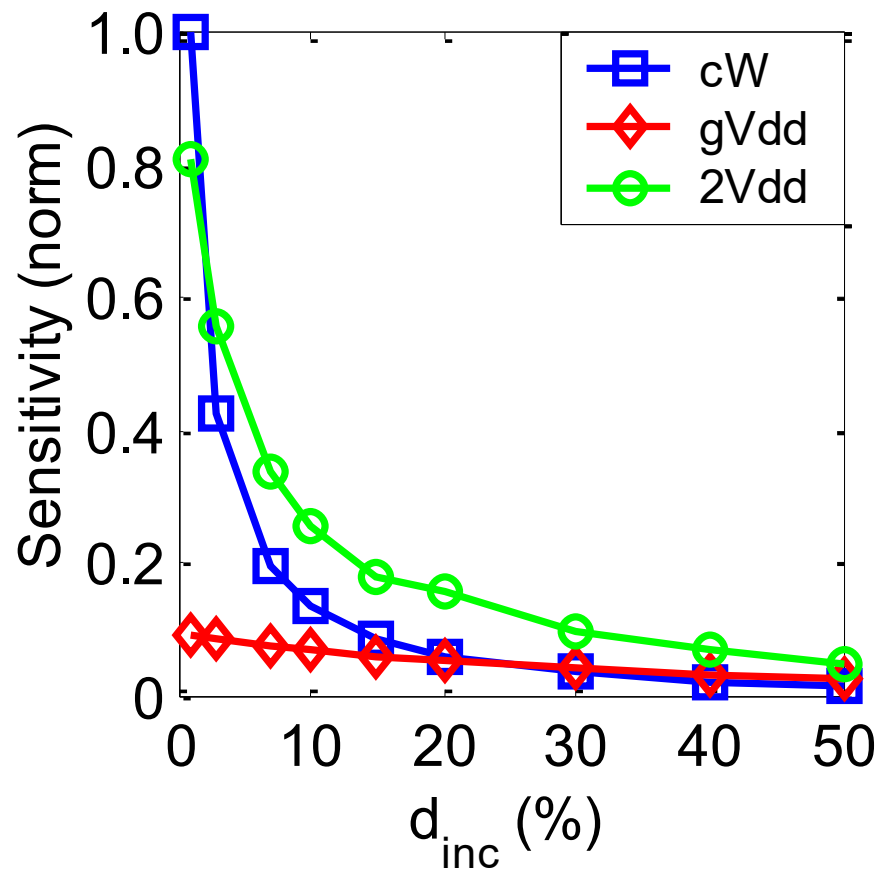
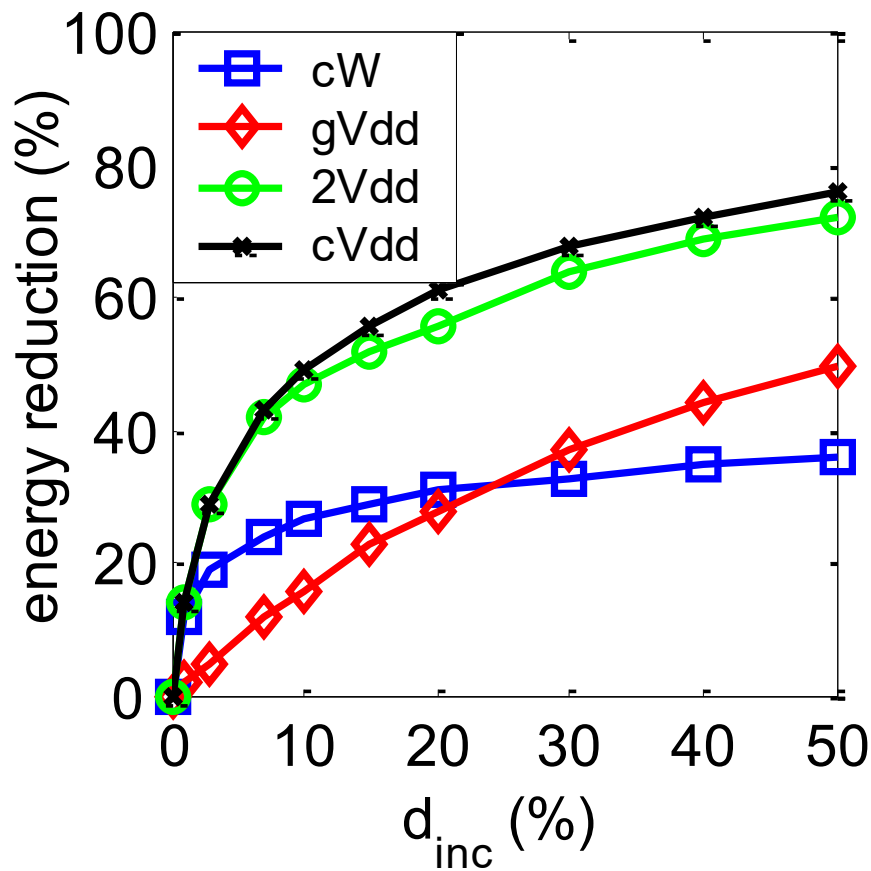
- Variable taper achieves minimum energy
- Reduce number of stages at large d_{inc}

Inverter Chain: V_{DD} Optimization



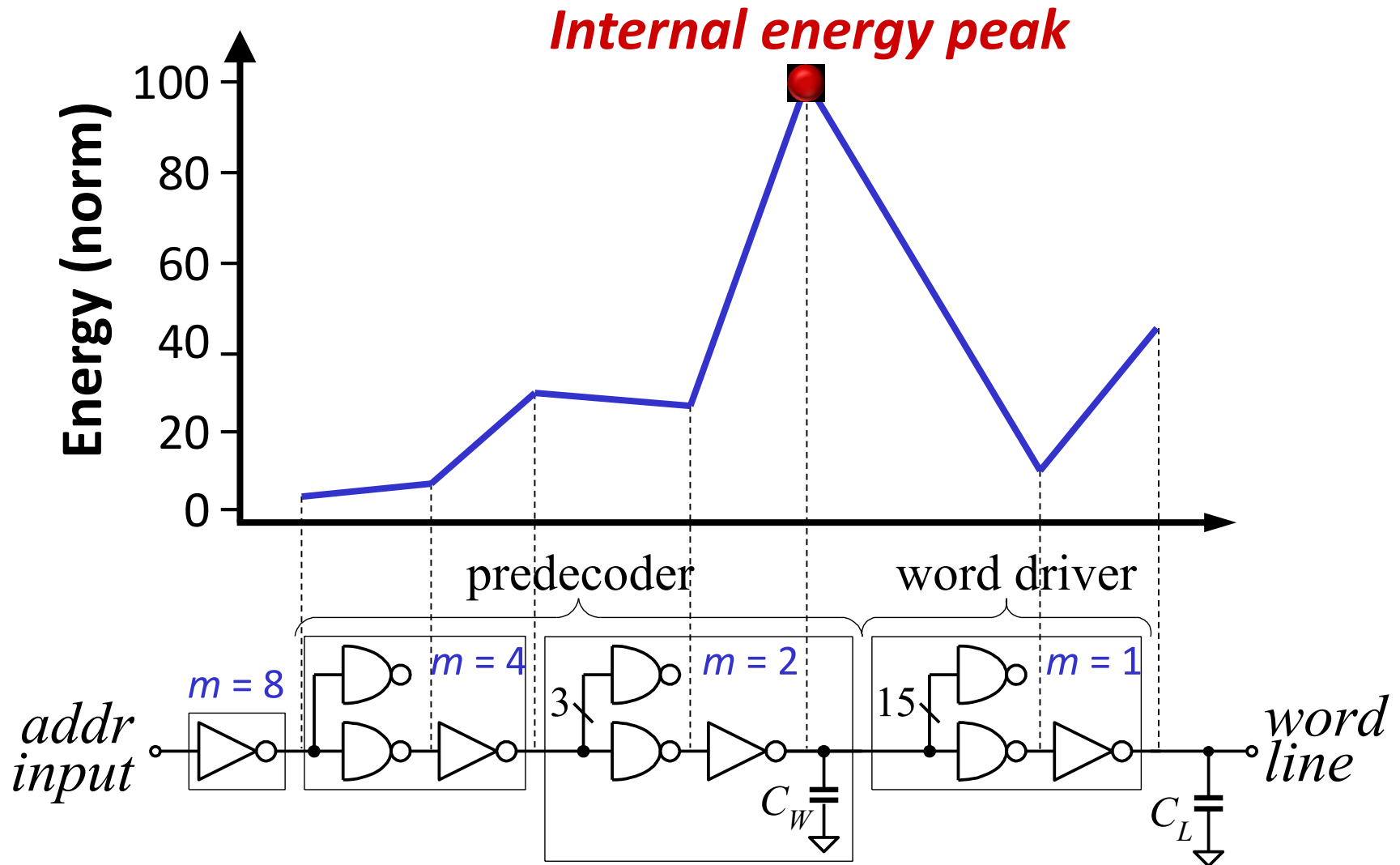
- Variable taper achieved by voltage scaling
- V_{DD} reduces energy of the final load first

Inverter Chain: Optimization Results

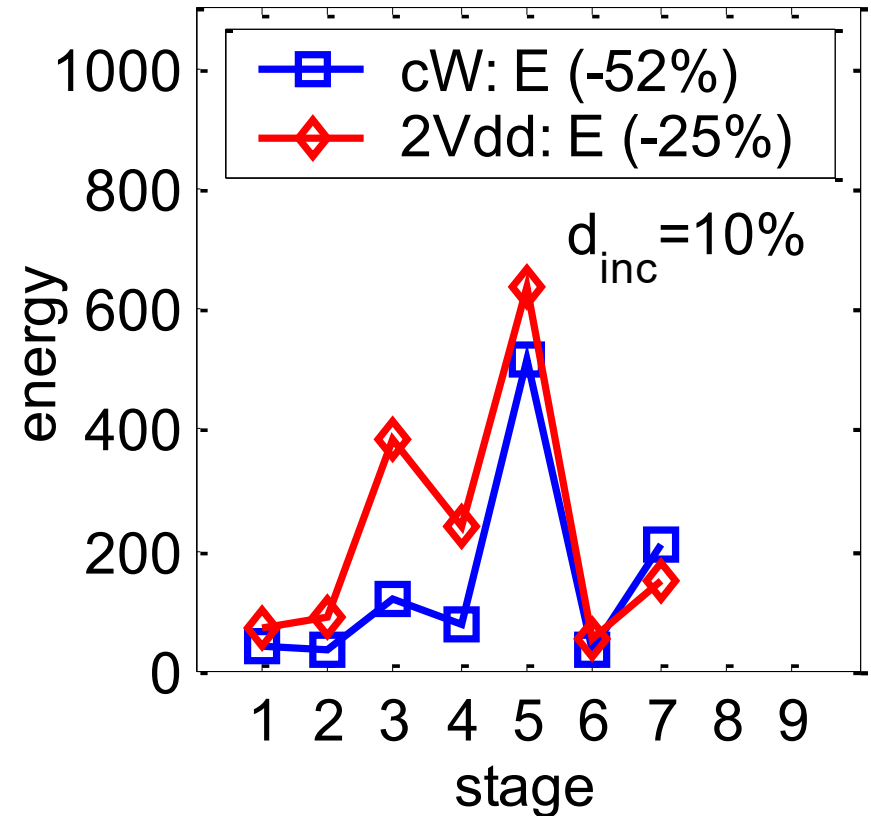
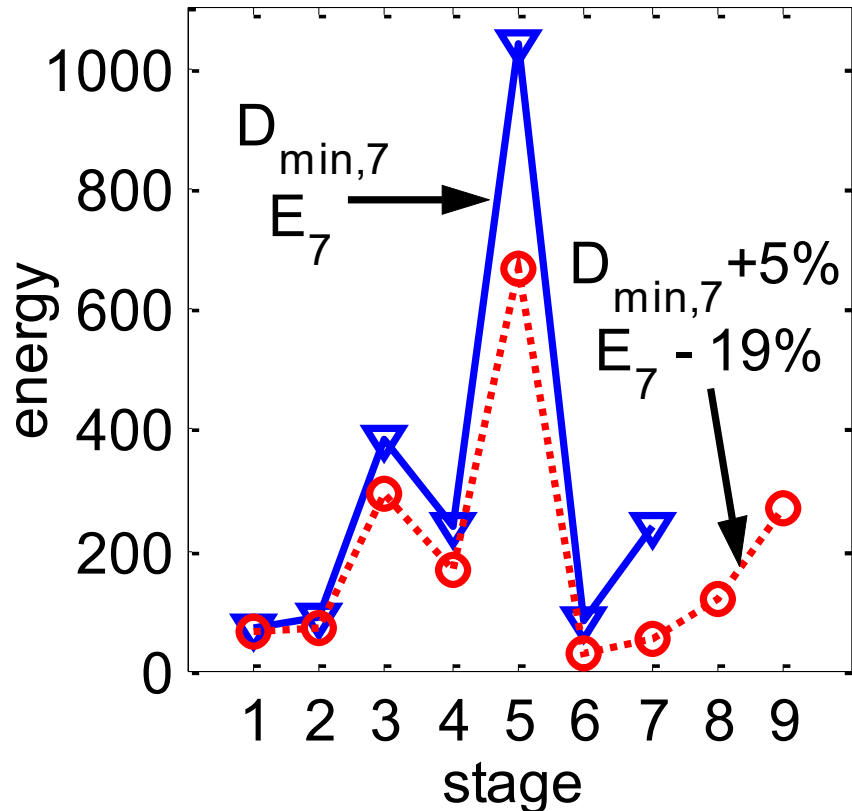


- Parameter with the largest sensitivity has the largest potential for energy reduction
- Two discrete supplies mimic per-stage V_{DD}

Example 14.2: SRAM Decoder

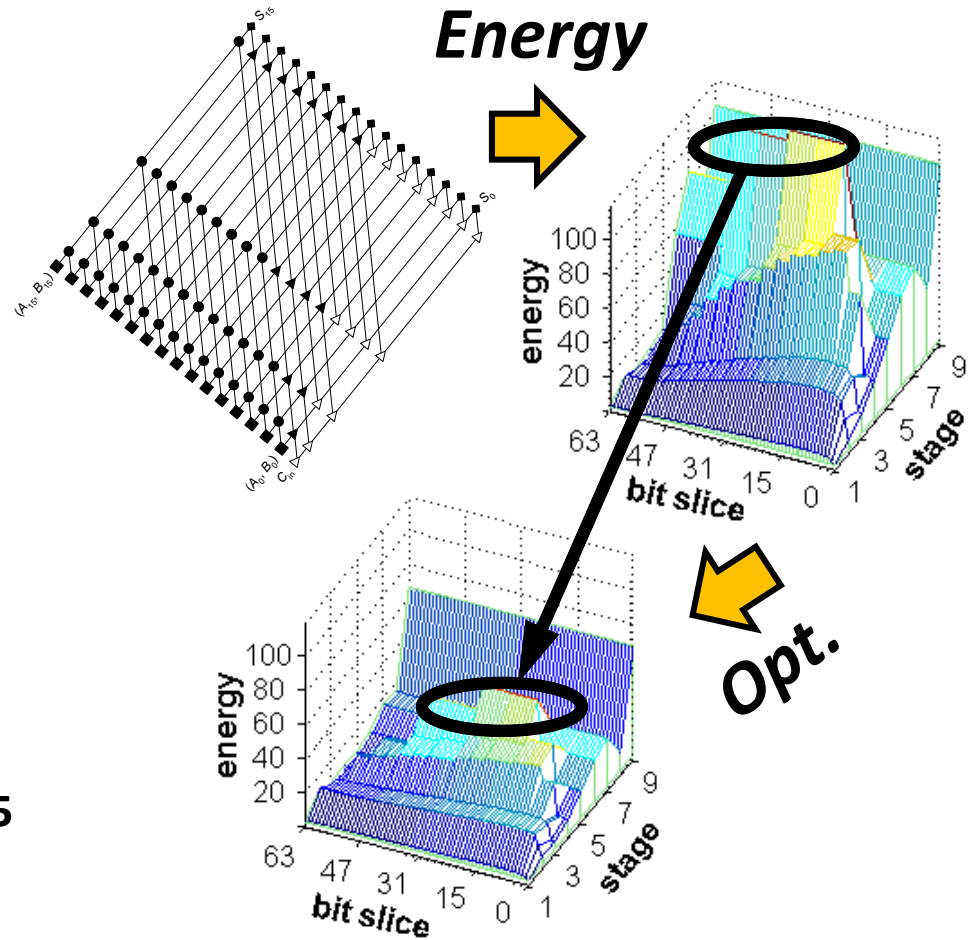
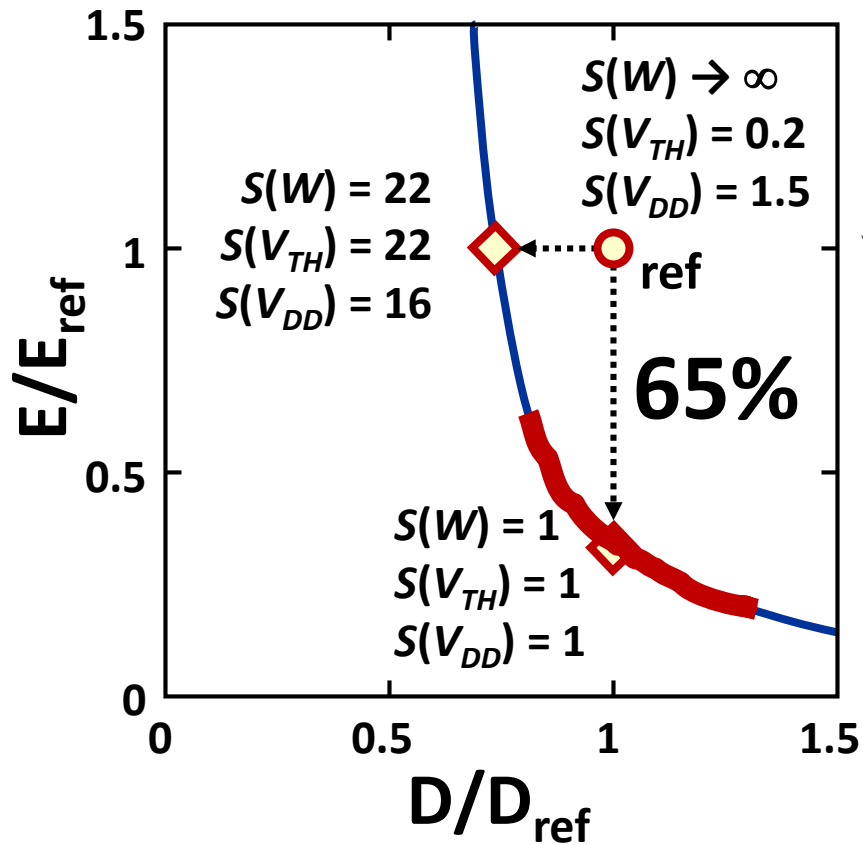


W vs. V_{DD} for Reducing Energy Peak



- V_{DD} less effective than W optimization
- Buffering also reduces energy peak

Example 14.3: Tree Adder

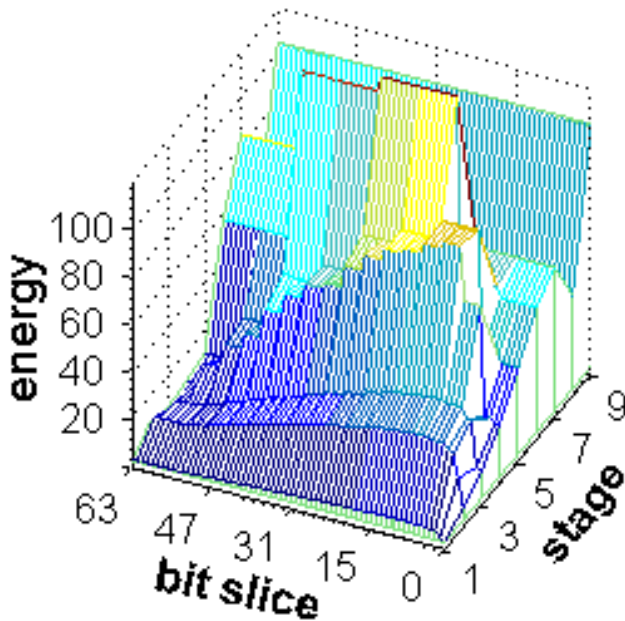


Tree Adder: Optimization Results

Reference: all paths are critical

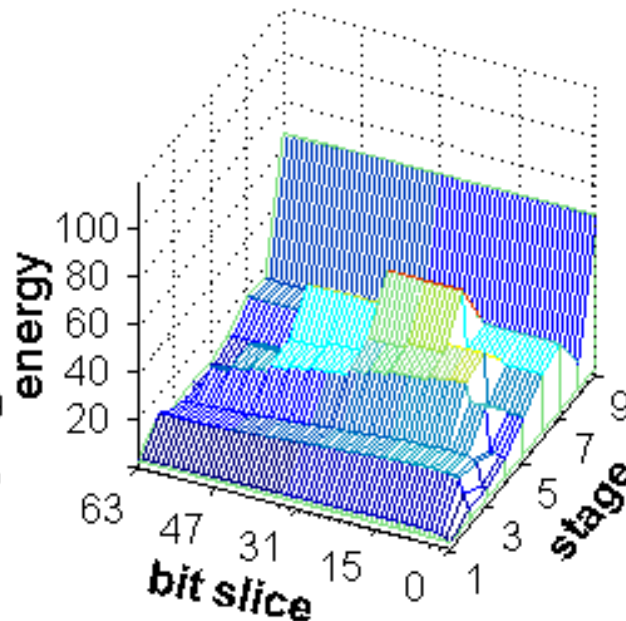
reference

$D_{\min}, E_{\text{ref}}$



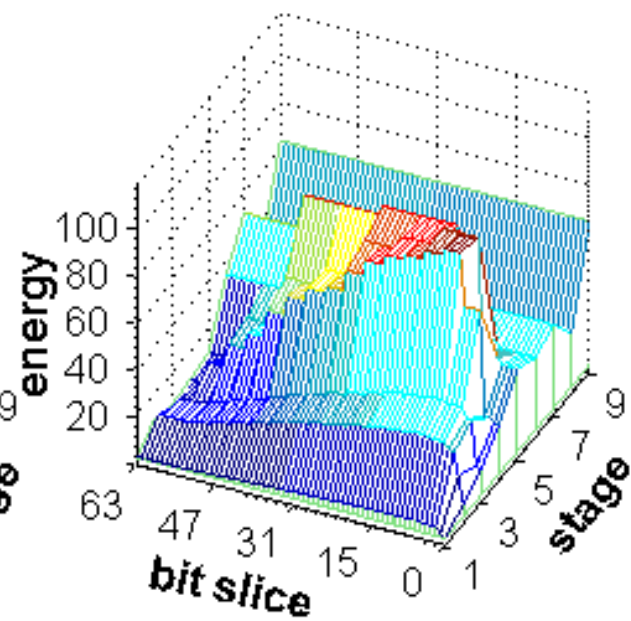
Sizing Opt.

$1.1D_{\min}, 0.45E_{\text{ref}}$



2- V_{DD} Opt.

$1.1D_{\min}, 0.73E_{\text{ref}}$

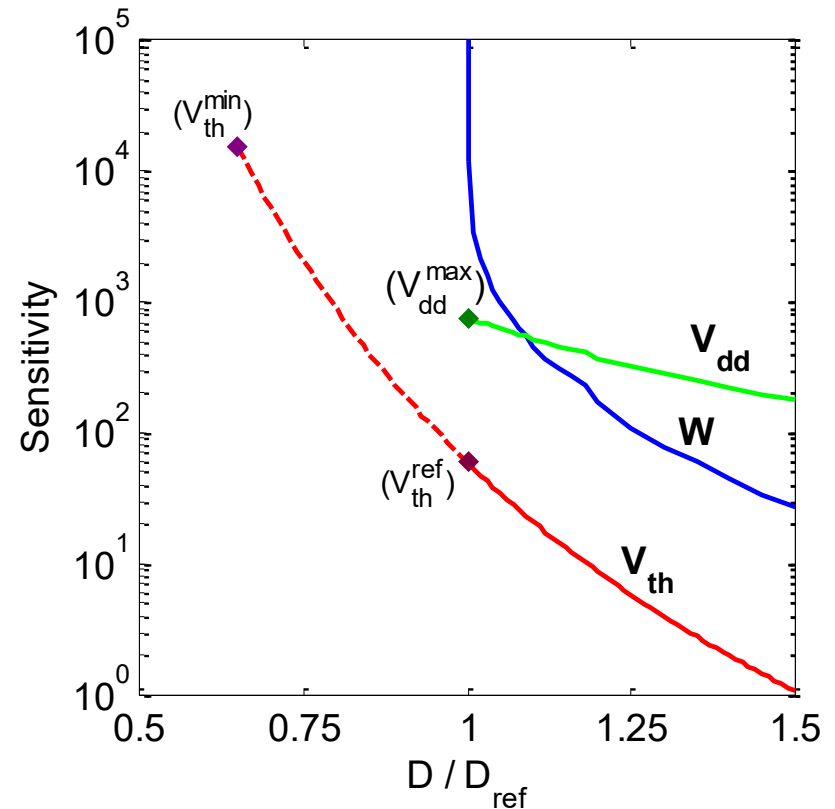
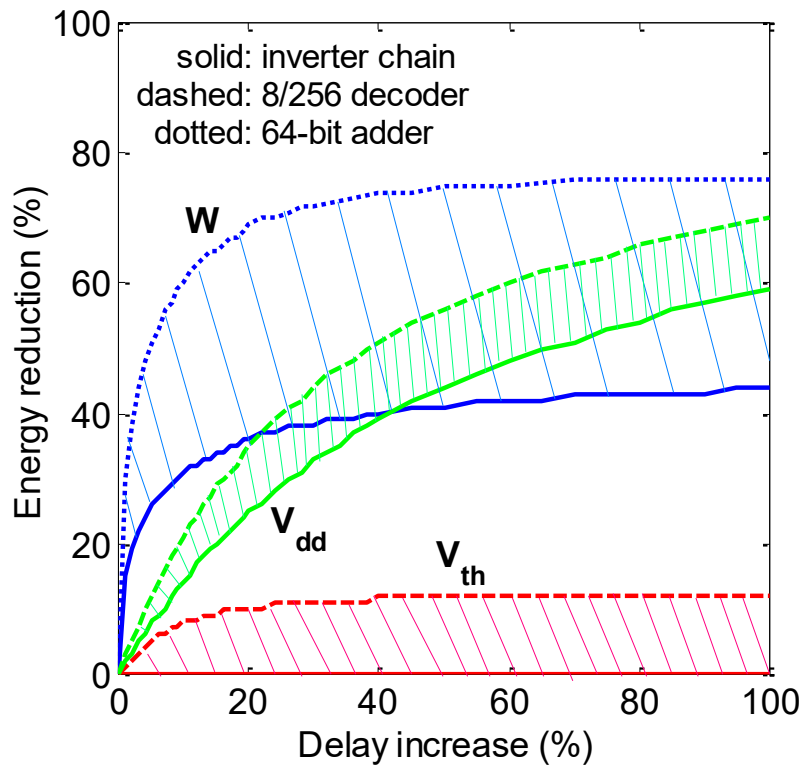


- Internal energy: W more effective than V_{DD}
 - For $d_{\text{inc}} = 10\%$: $\Delta E_W = -55\%$, $\Delta E_{2V_{DD}} = -27\%$

A Few Insights

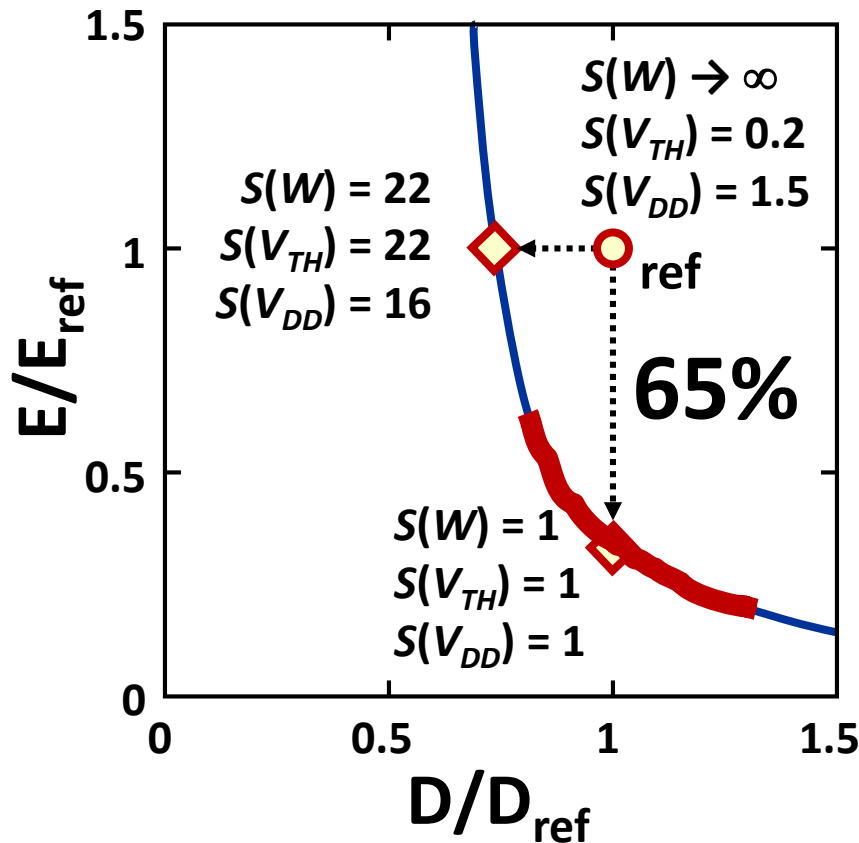
A Look at Tuning Variables...

10% excess delay $\rightarrow$ 30-70% energy reduction



Peak performance is very power inefficient!

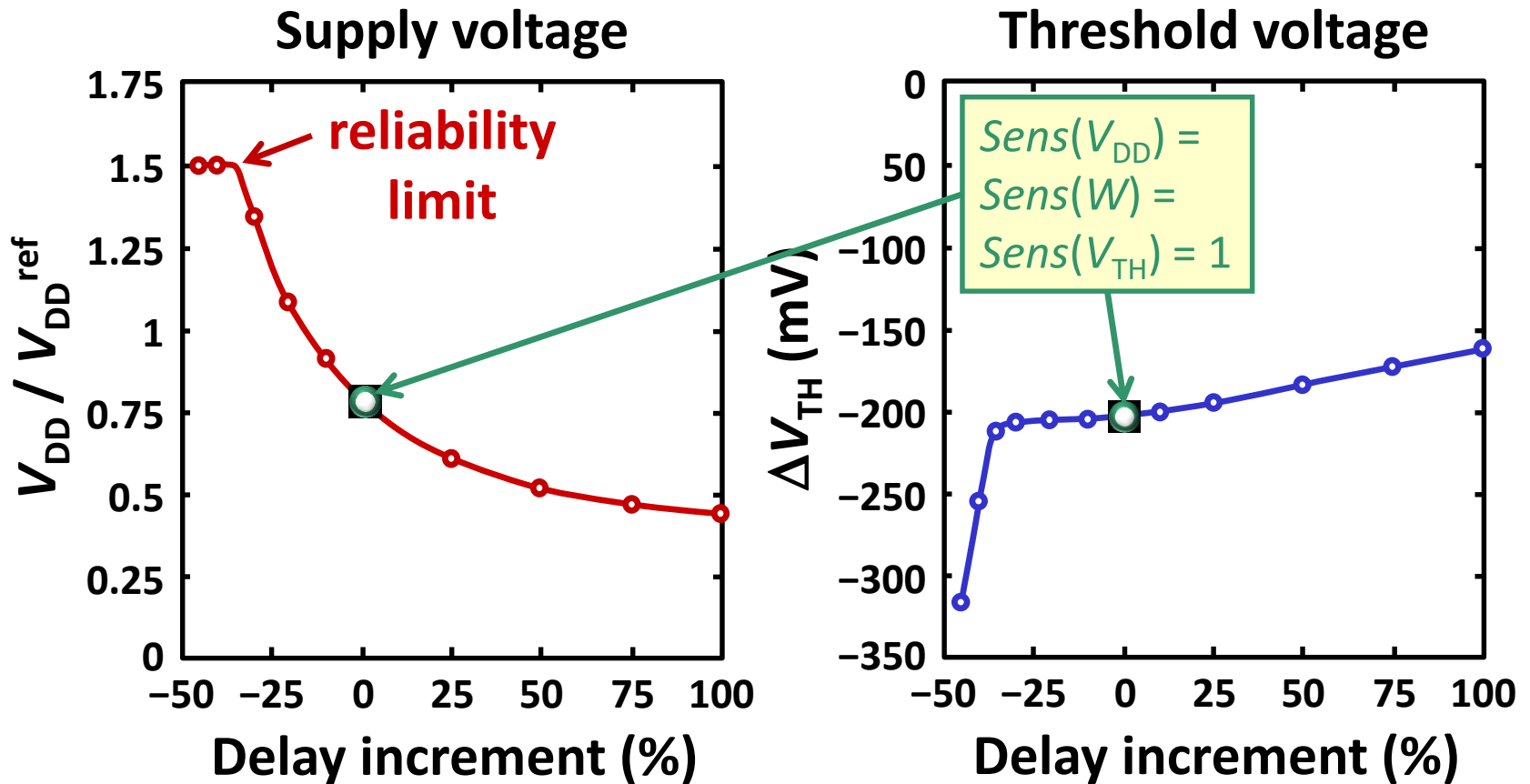
Limited Range of Circuit Optimization



- $\pm 30\%$ around D_{ref}
- Else, too much E or D
- Need for arch. opt.

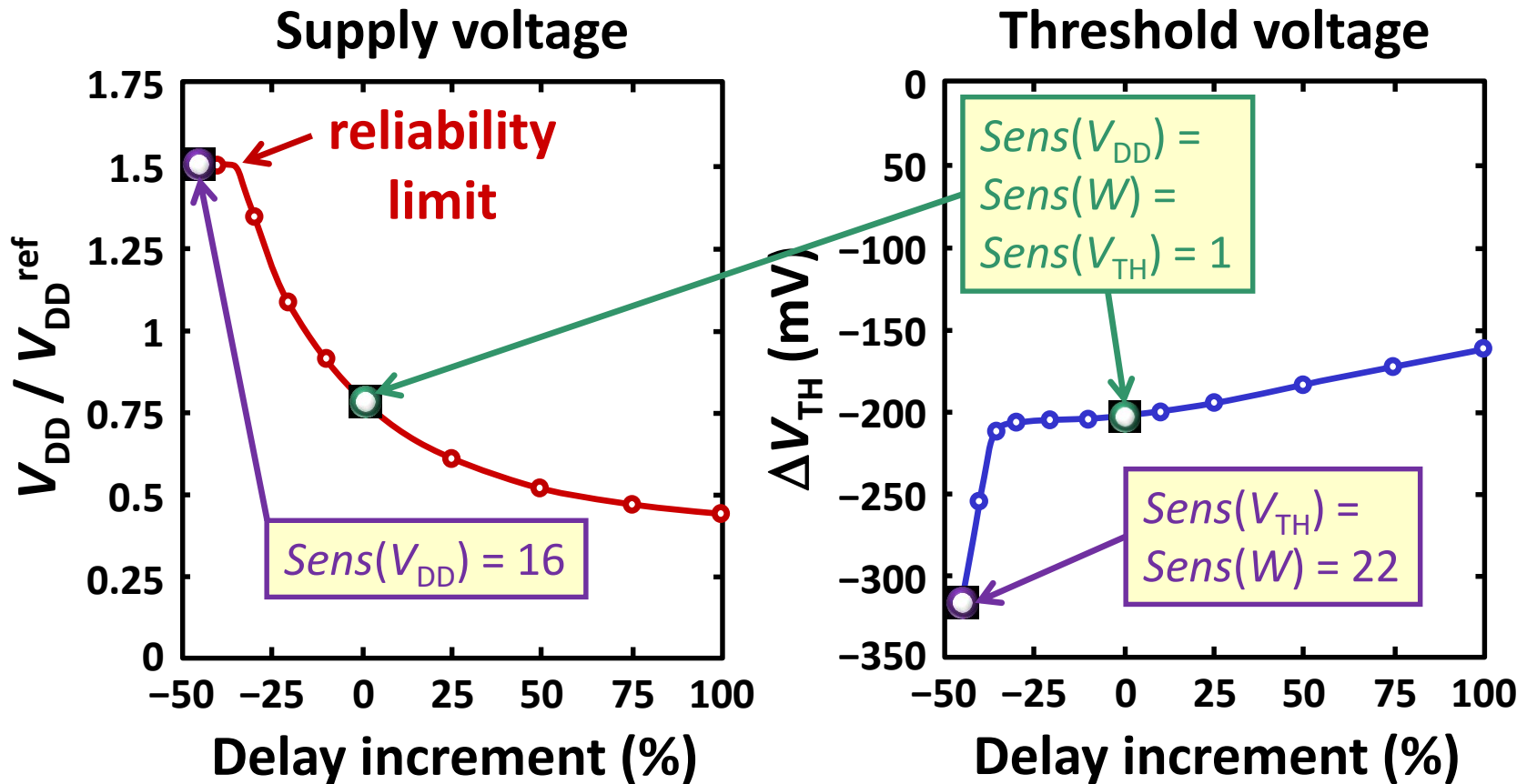
A Look at Tuning Variables

Equal sensitivity unless variables reach their bounds

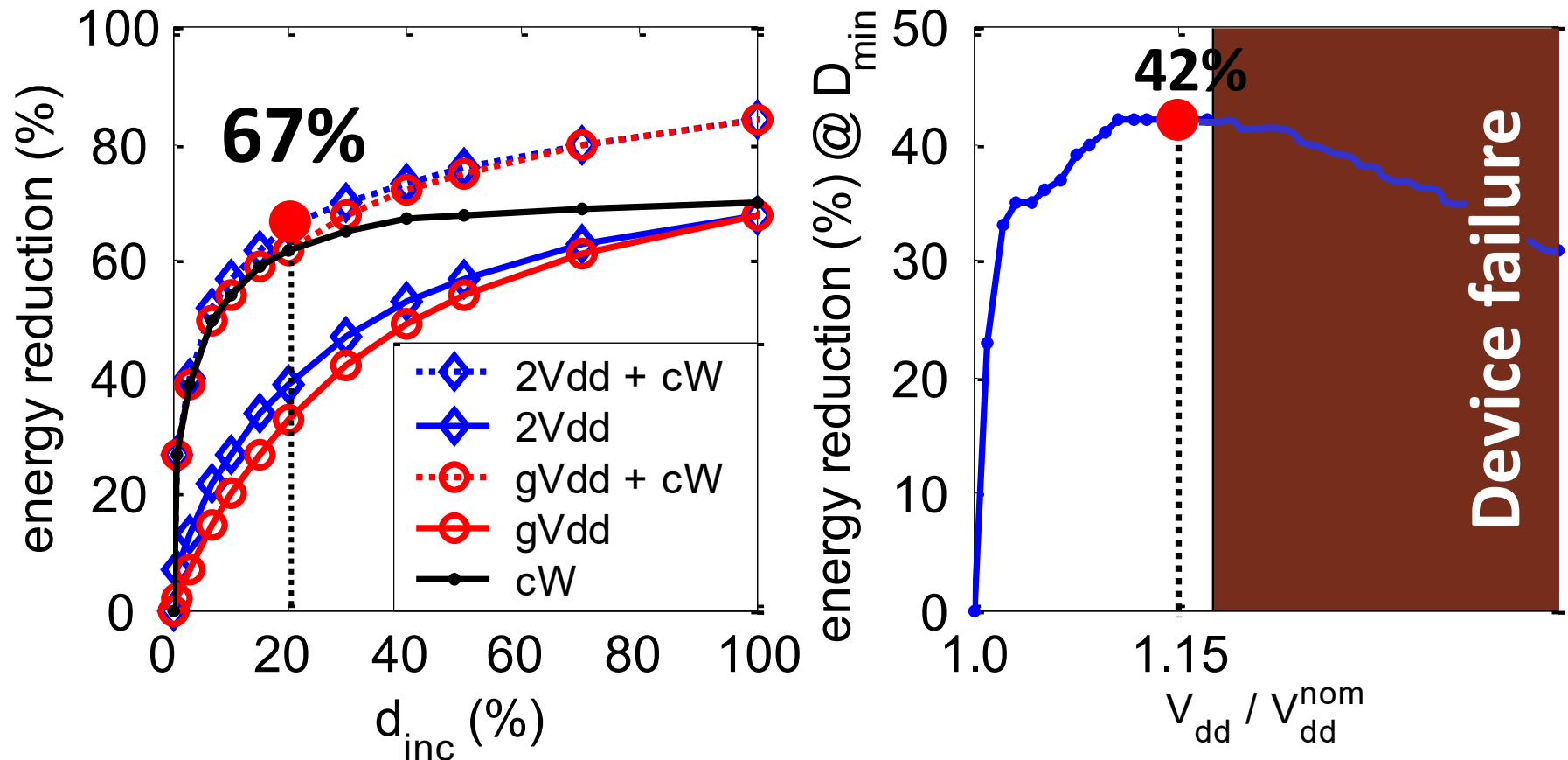


A Look at Tuning Variables

Bound reached = fewer variables to work with



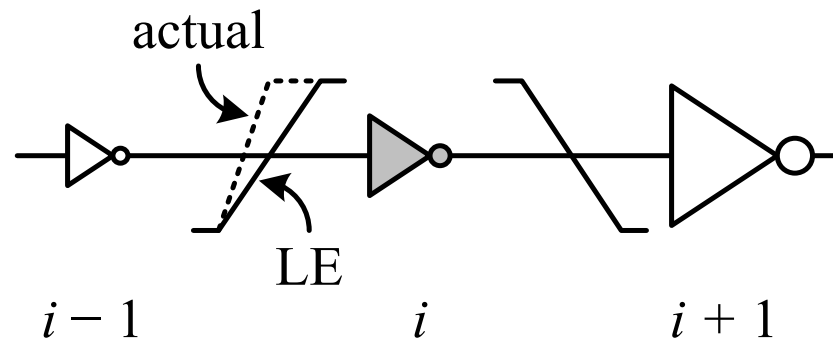
Tree Adder: Joint Optimization



- Higher V_{DD} yields a lower energy solution
- Choose a more efficient variable

An Update: Slope-Aware Delay Model

- Logical effort (equal slopes) overestimates delay



- Add **slope correction**

$$D = \sum_{i=1}^N \left(g_i \cdot h_i + p_i - \frac{g_i \cdot h_i - g_{i-1} \cdot h_{i-1}}{K_i} \right)$$

Gate & V_{DD}
dependent

Intuition: Slope Factor

$$t_p = t_{LE} - \frac{t_{slope,out} - t_{slope,in}}{K_{slope\ factor}}$$

Same RC 

$$t_p = t_{LE} - \tau \cdot \frac{f_{out} - f_{in}}{K_{FO\ factor}}$$

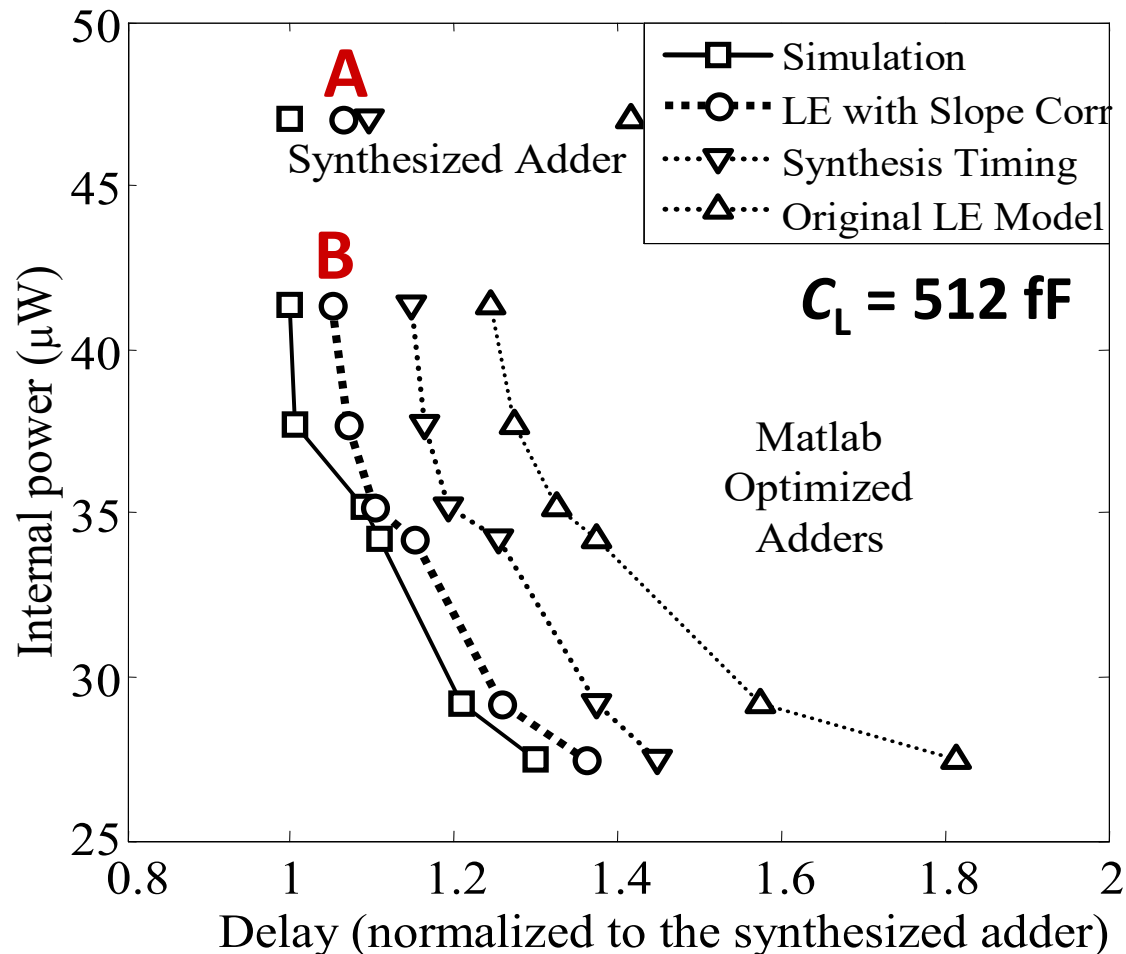
Divide by τ 

$$d = d_{LE} - \frac{f_{out} - f_{in}}{K_{gate}}$$

- **K_{gate} converts slope to delay (fanout)**
 - Should be around 2-ish

Result: 16-b Adder Example (H = 256)

Logical effort largely overestimates non-critical paths



- **A: LE sizing**

- **B: SC LE sizing**

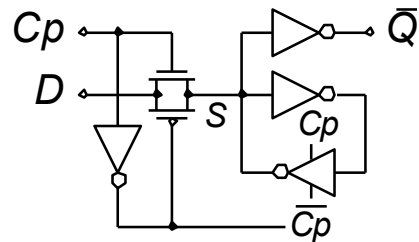
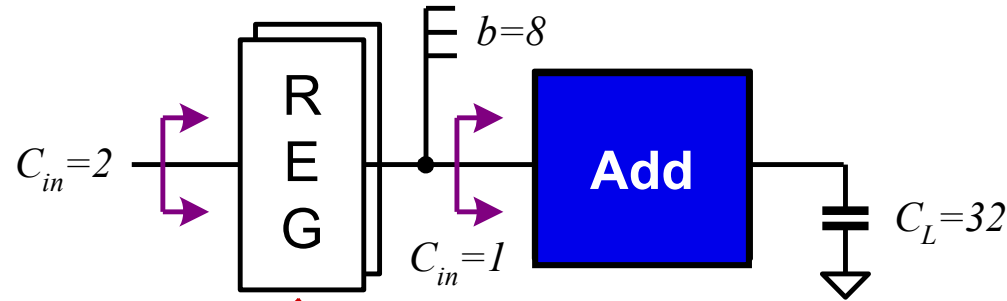
[C.C. Wang, D. Markovic,
TCAS-II, Aug'09]

Lessons from Circuit Optimization

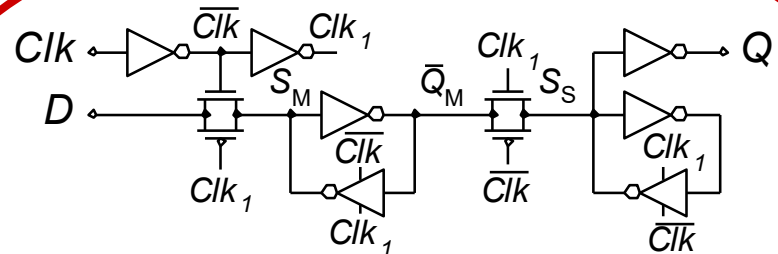
- **Sensitivity-based optimization framework**
 - Equal marginal costs $\Leftrightarrow$ Energy-efficient design
- **Effectiveness of tuning variables**
 - Sizing is the most effective for small d_{inc}
 - V_{DD} is better for large delay increments
- **Peak performance is VERY power inefficient**
 - $\sim 70\%$ energy reduction for 20% delay penalty
- **Limited performance range of tuning variables**
 - Additional variables for higher energy-efficiency

Choosing Circuit Topology: Optimal Register?

- 64-bit ALU



Cycle-latch (CL)

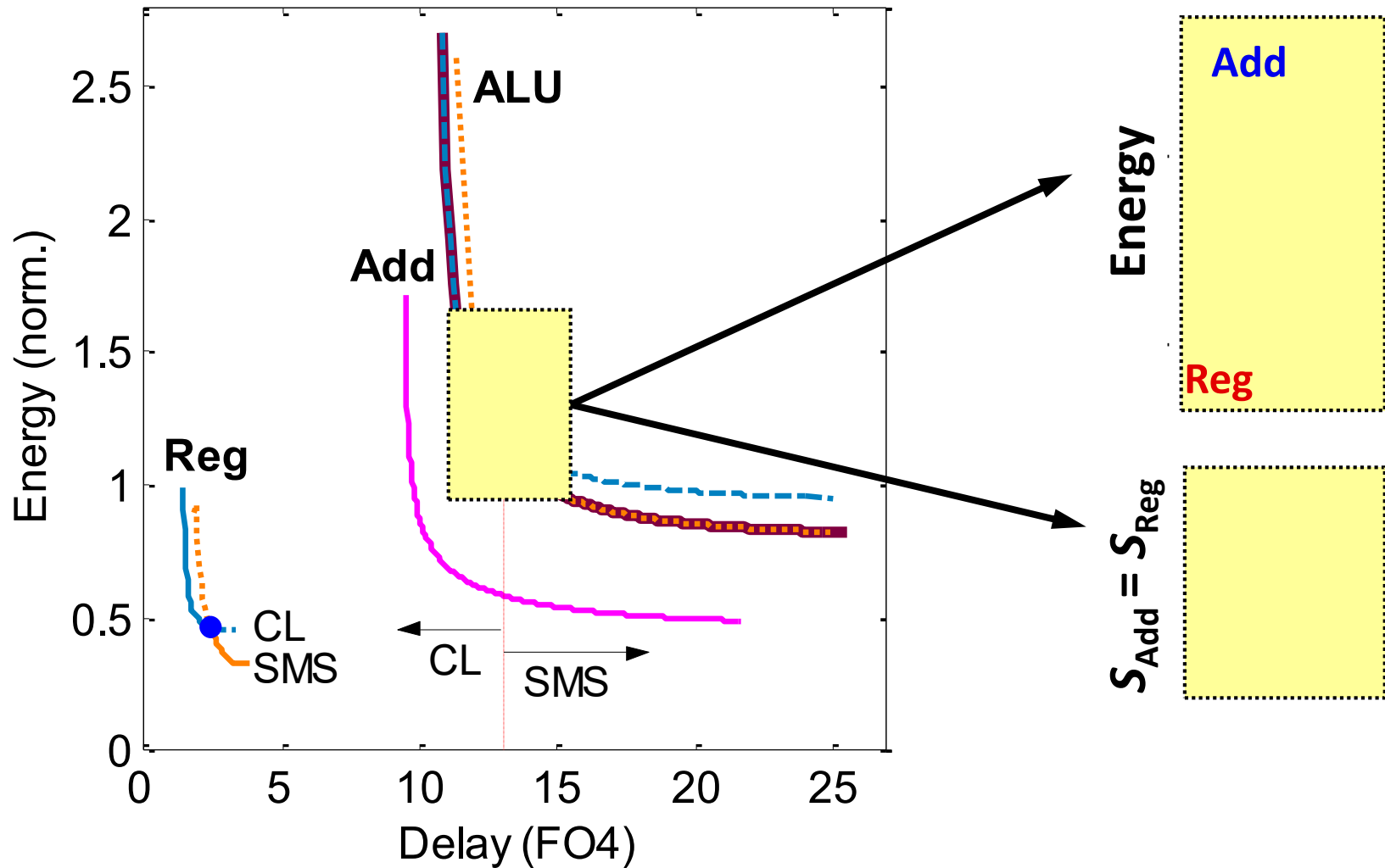


Static Master-Slave Latch-Pair (SMS)

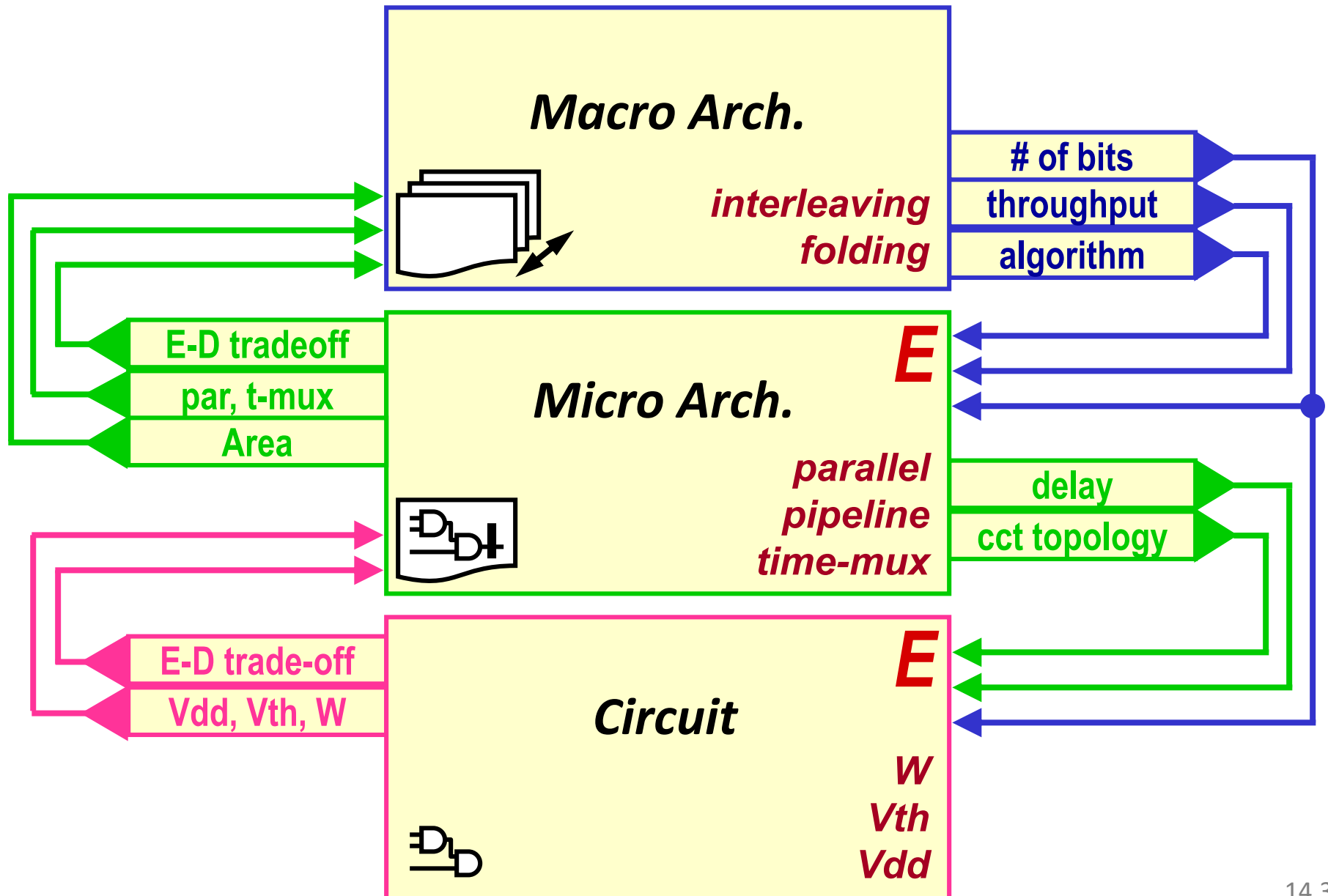
- Given energy-delay tradeoff for adder and register (two register options), what is the best energy-delay tradeoff in the ALU?

Balancing Sensitivity Across Circuit Blocks

Upsize lower activity blocks (Add) to save energy



Micro-Architectural Optimization

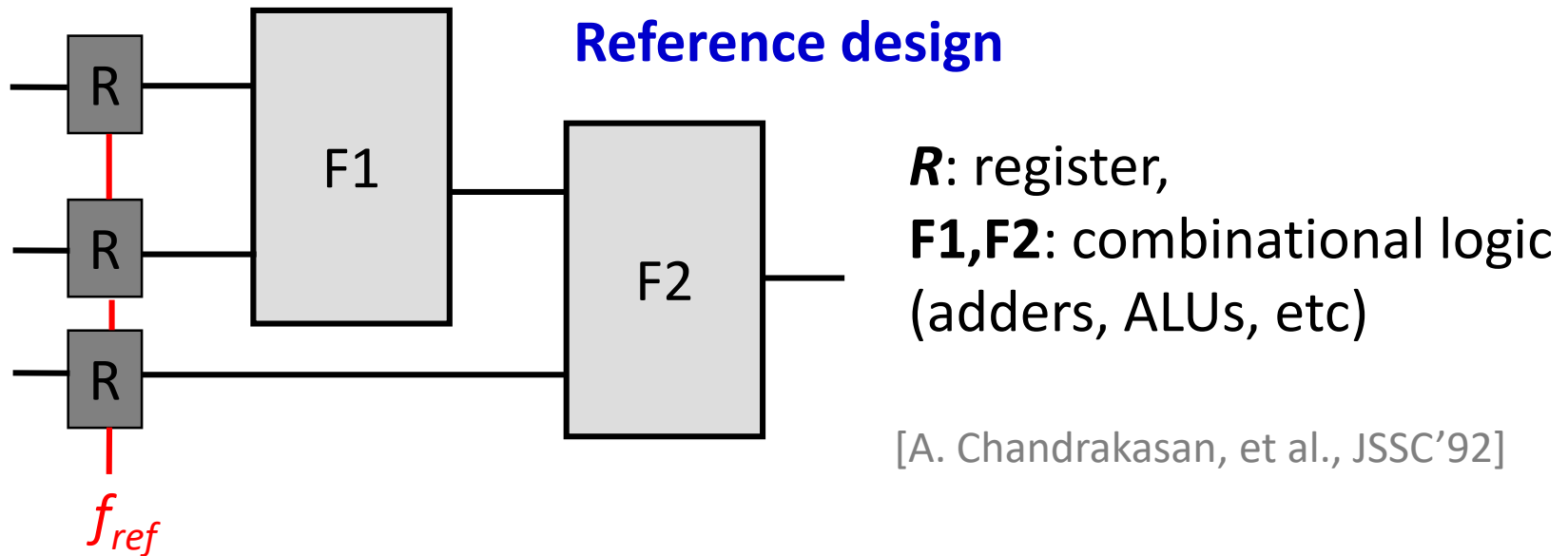


Reducing the Supply Voltage

(while maintaining performance)

Concurrency:

trading off clock frequency versus area to reduce power

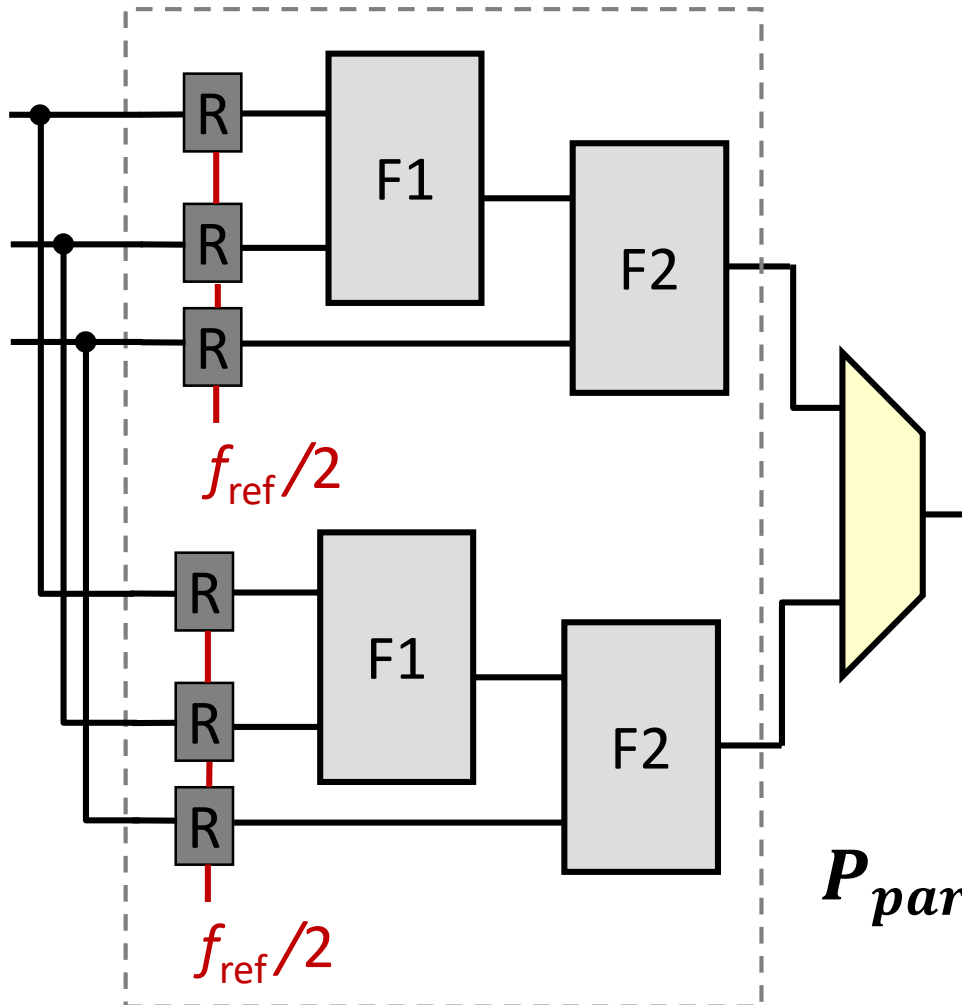


$$P_{ref} = C_{ref} \cdot V_{dd,ref}^2 \cdot f_{ref}$$

C_{ref} : average switching capacitance

A Parallel Implementation

- Slower logic = **lower** V_{DD} = lower power



$$f_{par} = \frac{f_{ref}}{2}$$

$$C_{par} = (2 + ov_{par}) \cdot C_{ref}$$

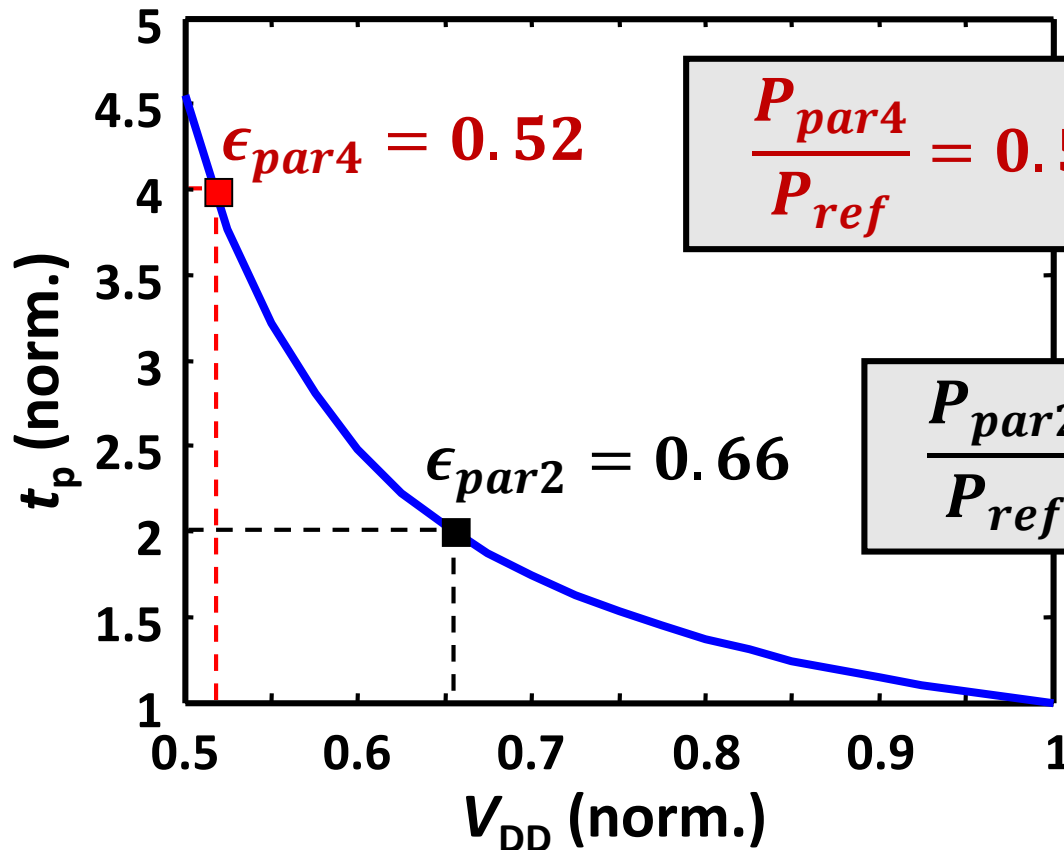
$$V_{DD,par} = \epsilon_{par} \cdot V_{DD,ref}$$

Power saving Almost cancels

$$P_{par} = \epsilon_{par}^2 \cdot \frac{2 + ov_{par}}{2} \cdot P_{ref}$$

Parallelism Example (90nm CMOS)

Power (assuming $ov_{par} = 7.5\%$)



$$\frac{P_{par4}}{P_{ref}} = 0.52^2 \cdot \frac{4.3}{4} = 0.29$$

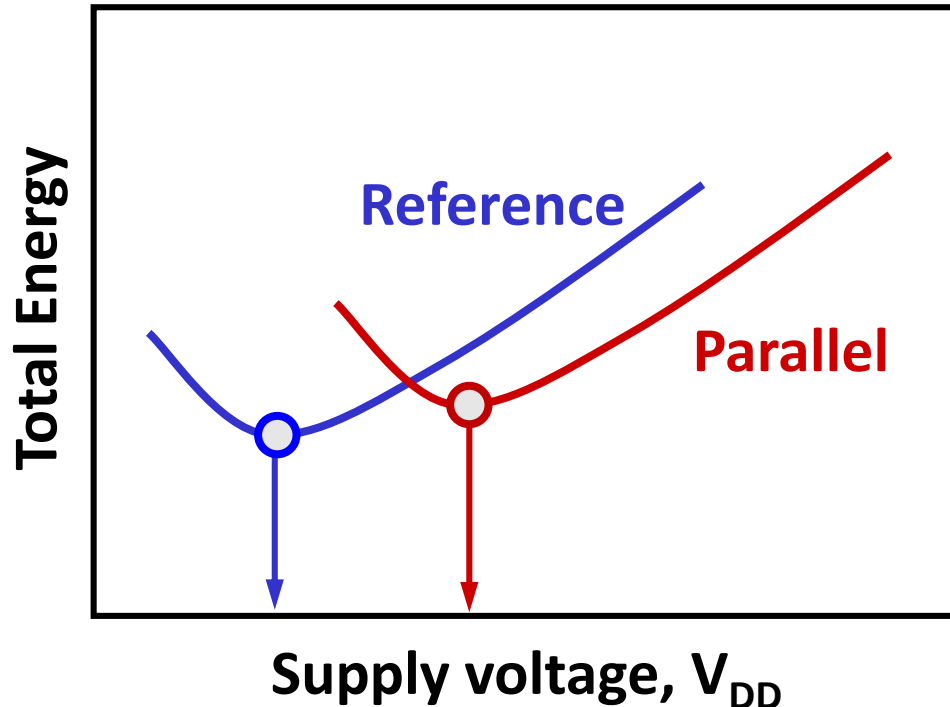
$$\frac{P_{par2}}{P_{ref}} = 0.66 \cdot \frac{2.15}{4} = 0.47$$

From: J. Rabaey (UCB)

How many levels of parallelism?

The More Parallel the Better?

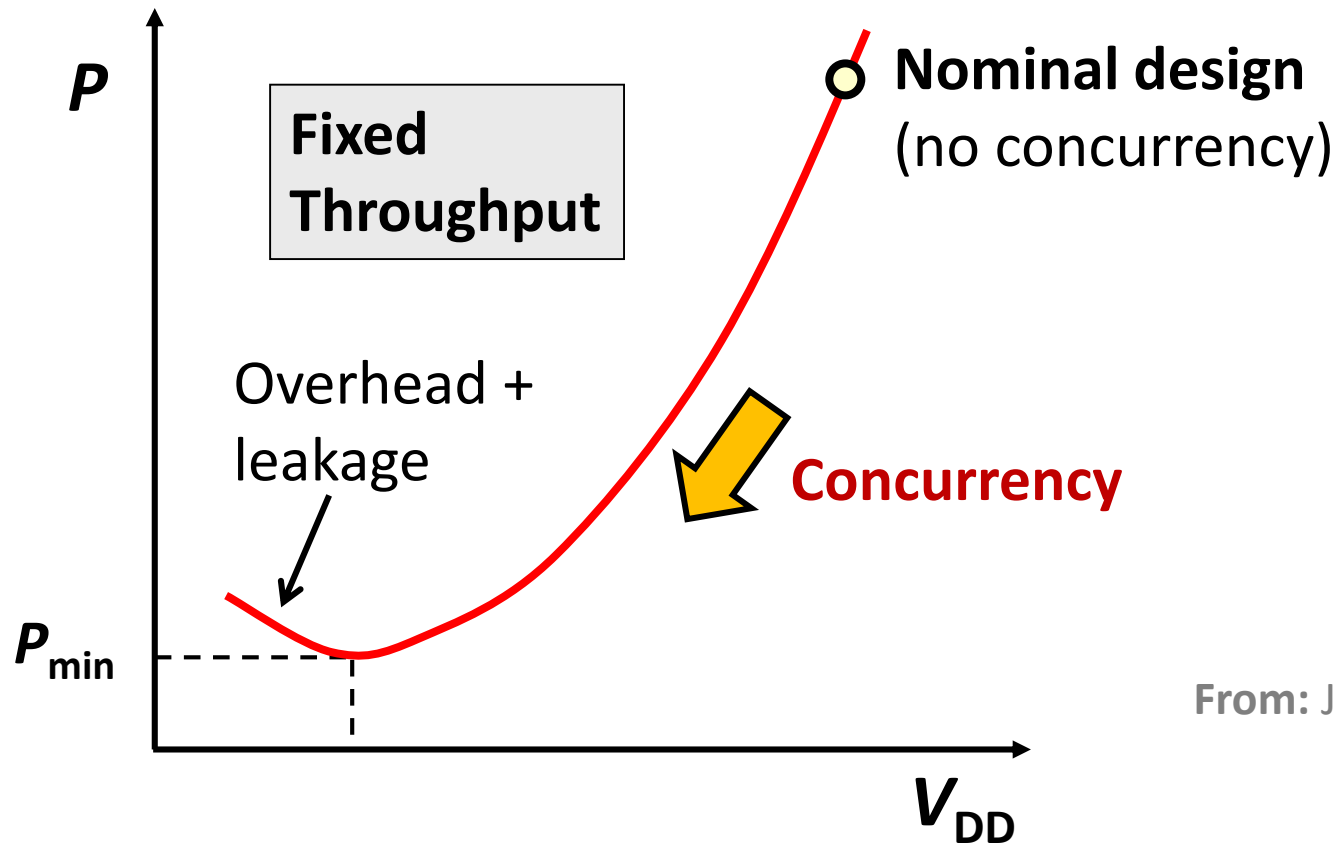
$$E_{tot} = E_{sw} + N \cdot E_{lk} + E_{overhad}$$



From:
J. Rabaey
(UCB)

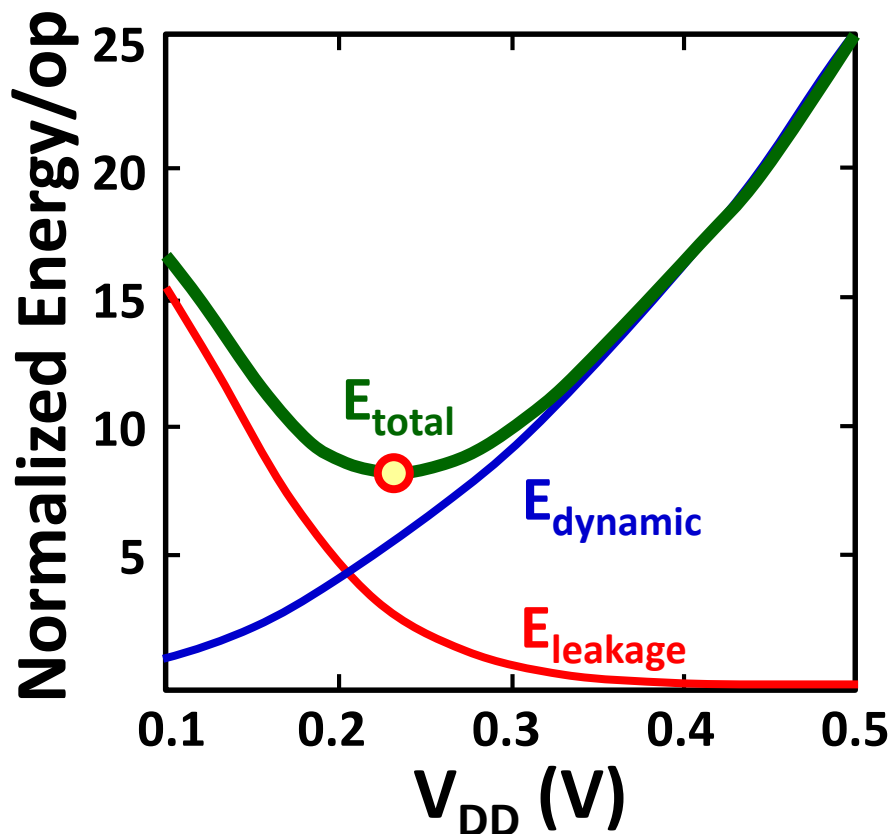
- Leakage and overhead start to dominate at high P
- Optimal V_{DD} and min E increase with parallelism

Increasing use of Concurrency Saturates

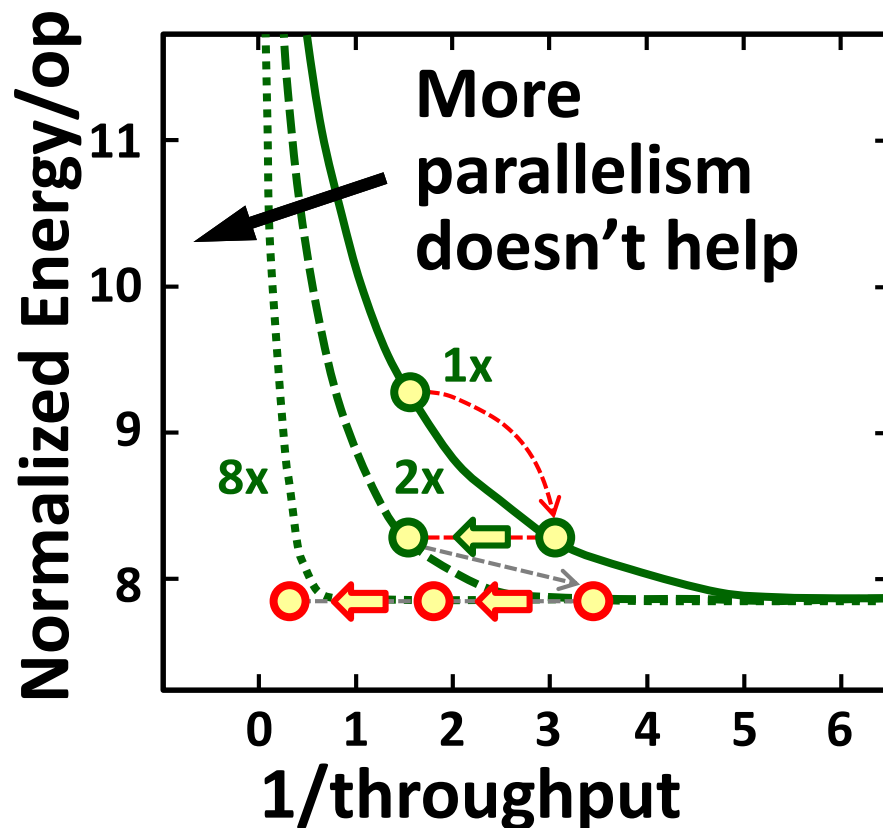


From: J. Rabaey (UCB)

Subthreshold Leakage: Game Over for CMOS



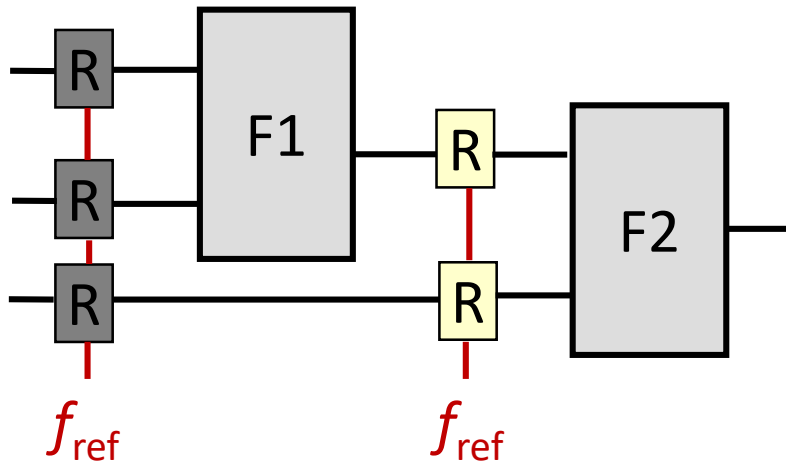
- Leakage and sub-threshold slope define minimum energy/op for CMOS



- Parallelism cannot reduce energy/op if operating at minimum energy/op

A Pipelined Implementation

Shallower logic reduces required supply voltage



$$f_{pipe} = f_{ref}$$

$$C_{pipe} = (1 + ov_{pipe}) \cdot C_{ref}$$

$$V_{DD,pipe} = \epsilon_{pipe} \cdot V_{DD,ref}$$

Power saving Typically small

$$P_{pipe} = \text{[Red Box]} \cdot \text{[Yellow Box]} \cdot P_{ref}$$

Comparison of Par/Pipe @ Same V_{DD}

Parallel
($ov_{par} = 7.5\%$)

$$\frac{P_{par4}}{P_{ref}} = 0.52^2 \cdot \frac{4.3}{4} = \boxed{}$$

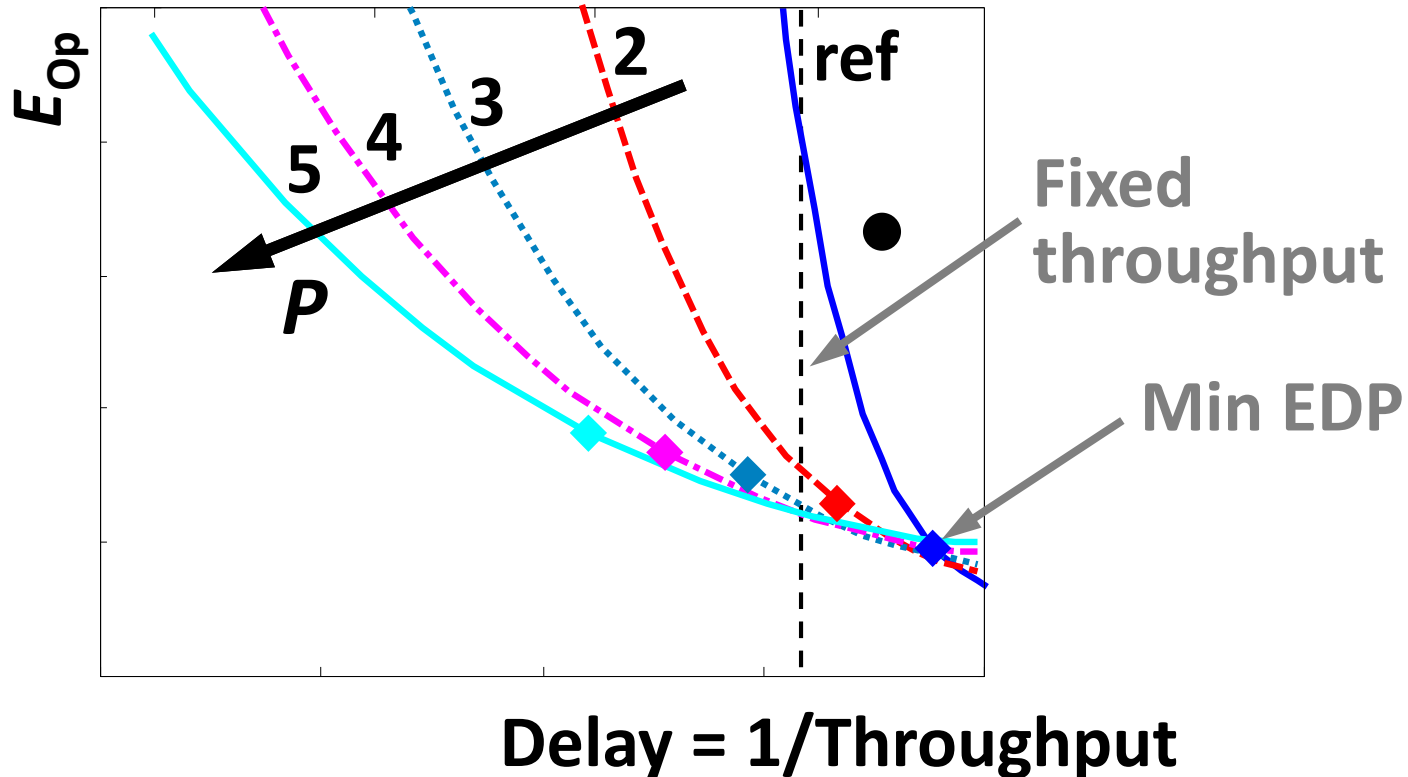
$$\frac{P_{par2}}{P_{ref}} = 0.66 \cdot \frac{2.15}{4} = \boxed{}$$

Pipeline
($ov_{par} = 10\%$)

$$\frac{P_{pipe4}}{P_{ref}} = 0.52^2 \cdot 1.1 = \boxed{}$$

$$\frac{P_{pipe2}}{P_{ref}} = 0.662 \cdot 1.1 = \boxed{}$$

Energy-Delay Space

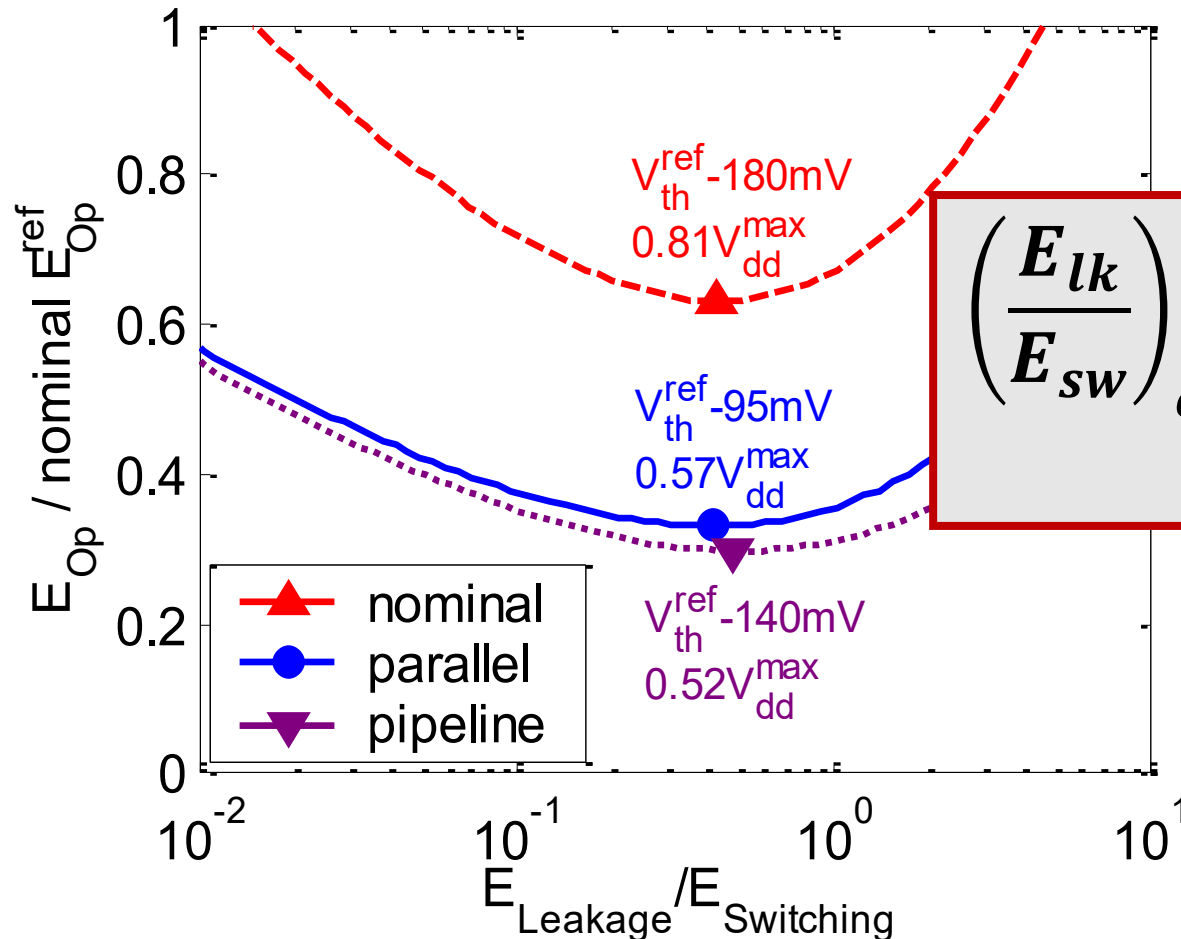


- Level of concurrency depends on target performance
- **Rule of thumb:** if speed exceeds MEP, add parallelism

Optimal Designs Have High Leakage

Set V_T , find V_{DD} to min E_{Op} for a fixed performance

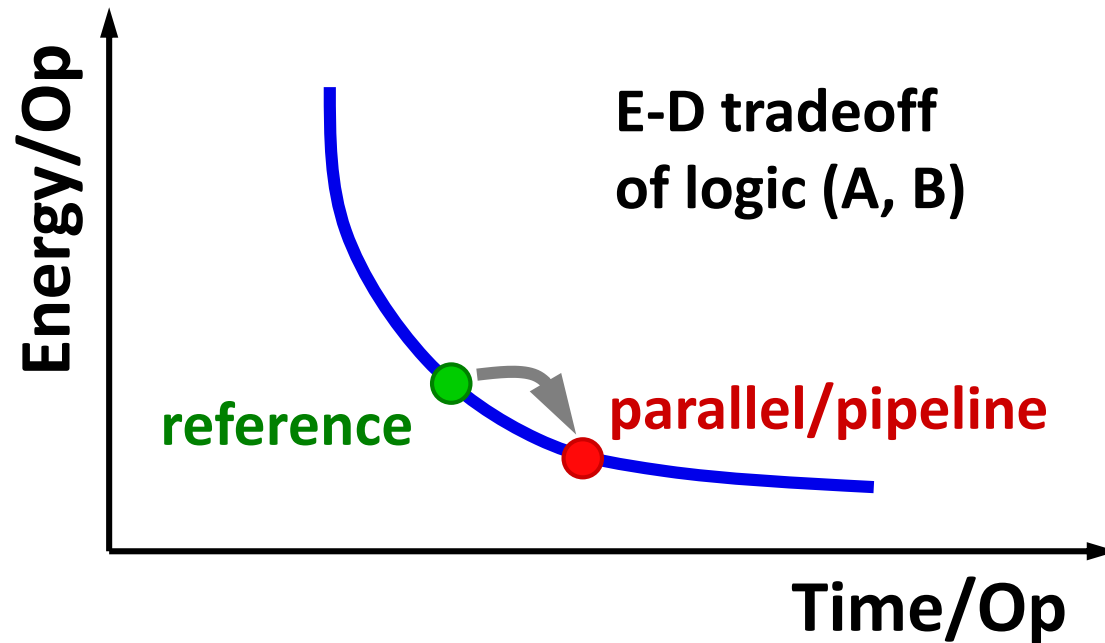
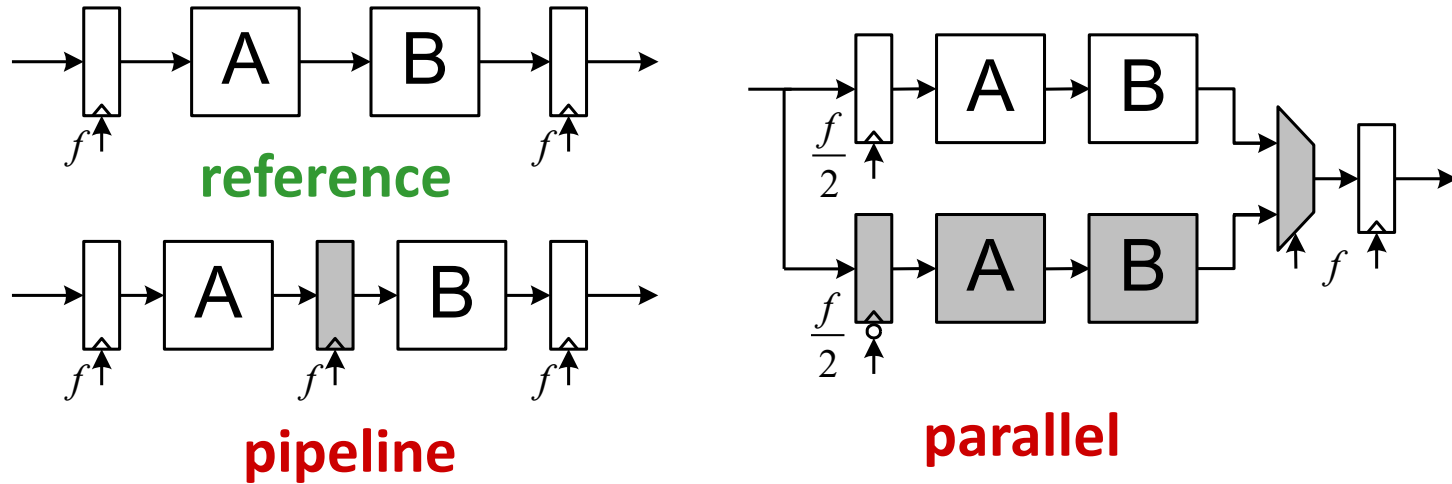
from 13.6



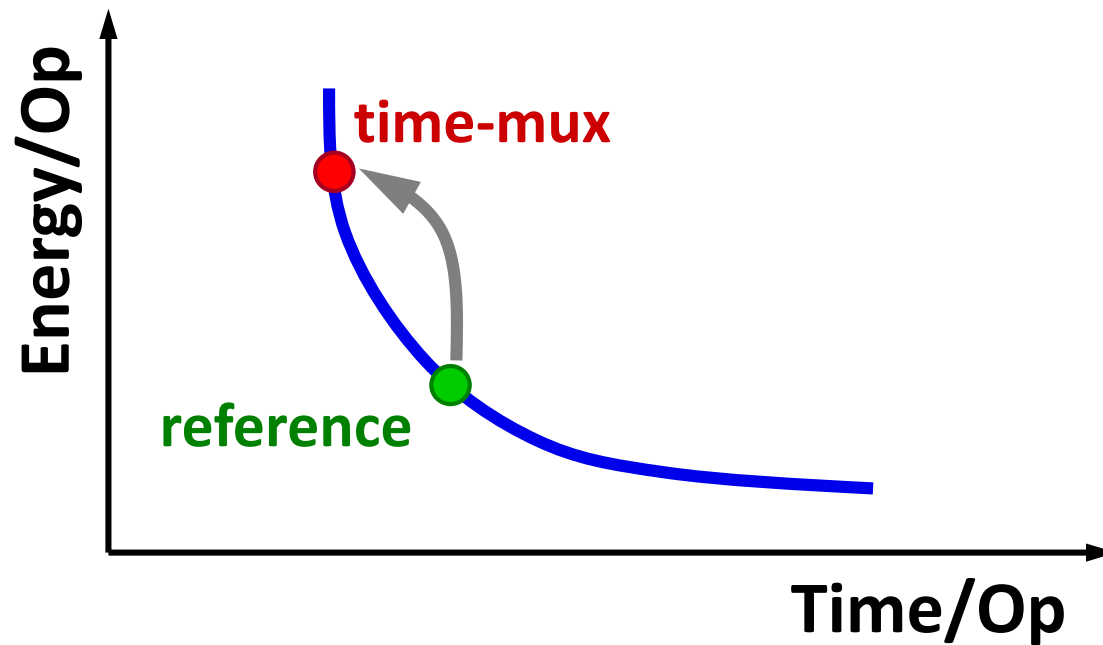
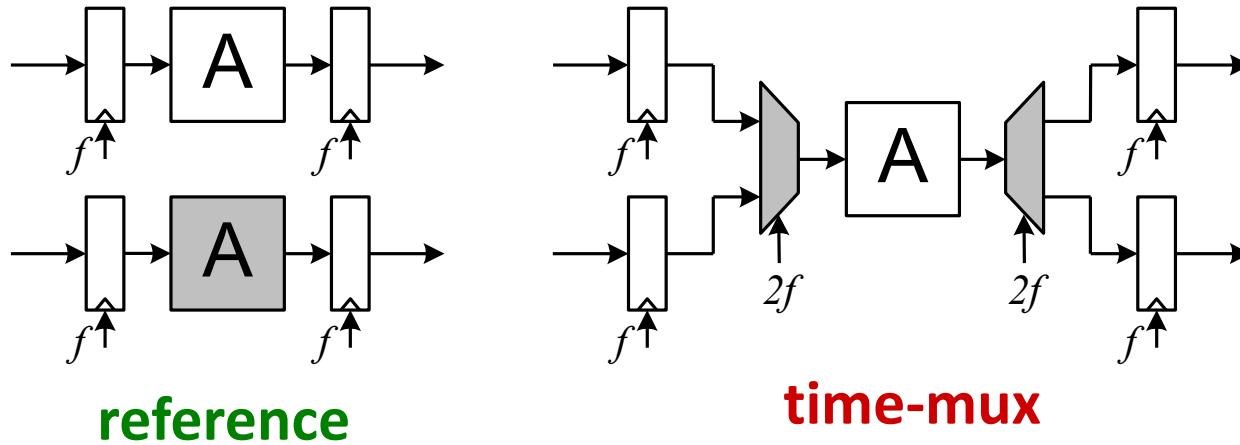
$$\left(\frac{E_{lk}}{E_{sw}} \right)_{opt} = \frac{2}{\ln \left(\frac{L_d}{\alpha_{avg}} \right) - K}$$

Topology	Inv	Add	Dec
$(E_{Lk}/E_{Sw})^{opt}$	0.8	0.5	0.2

Parallelism and Pipelining in E-D Space

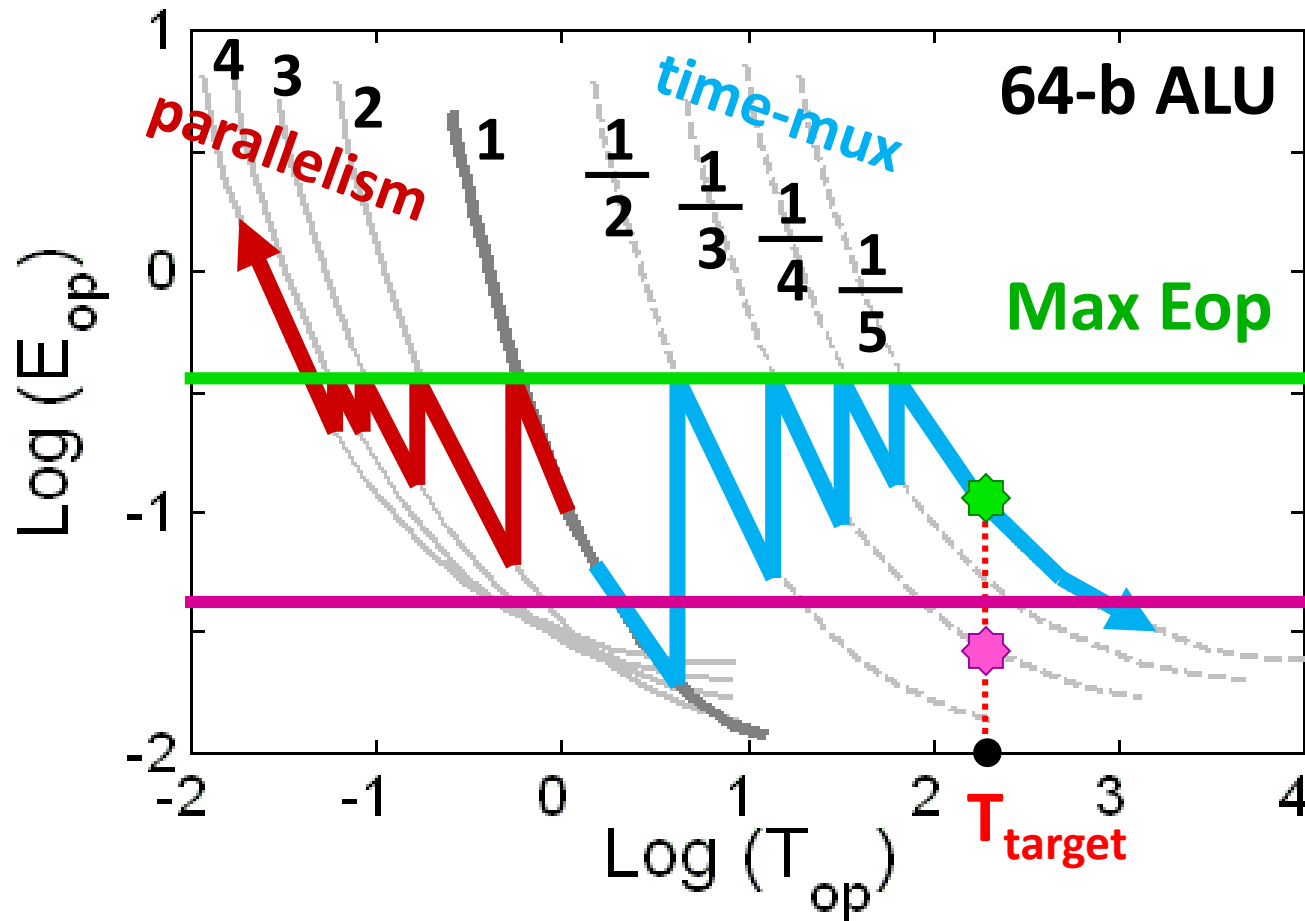


Time Multiplexing



Energy-Area Tradeoff

High throughput: Parallelism = Large Area



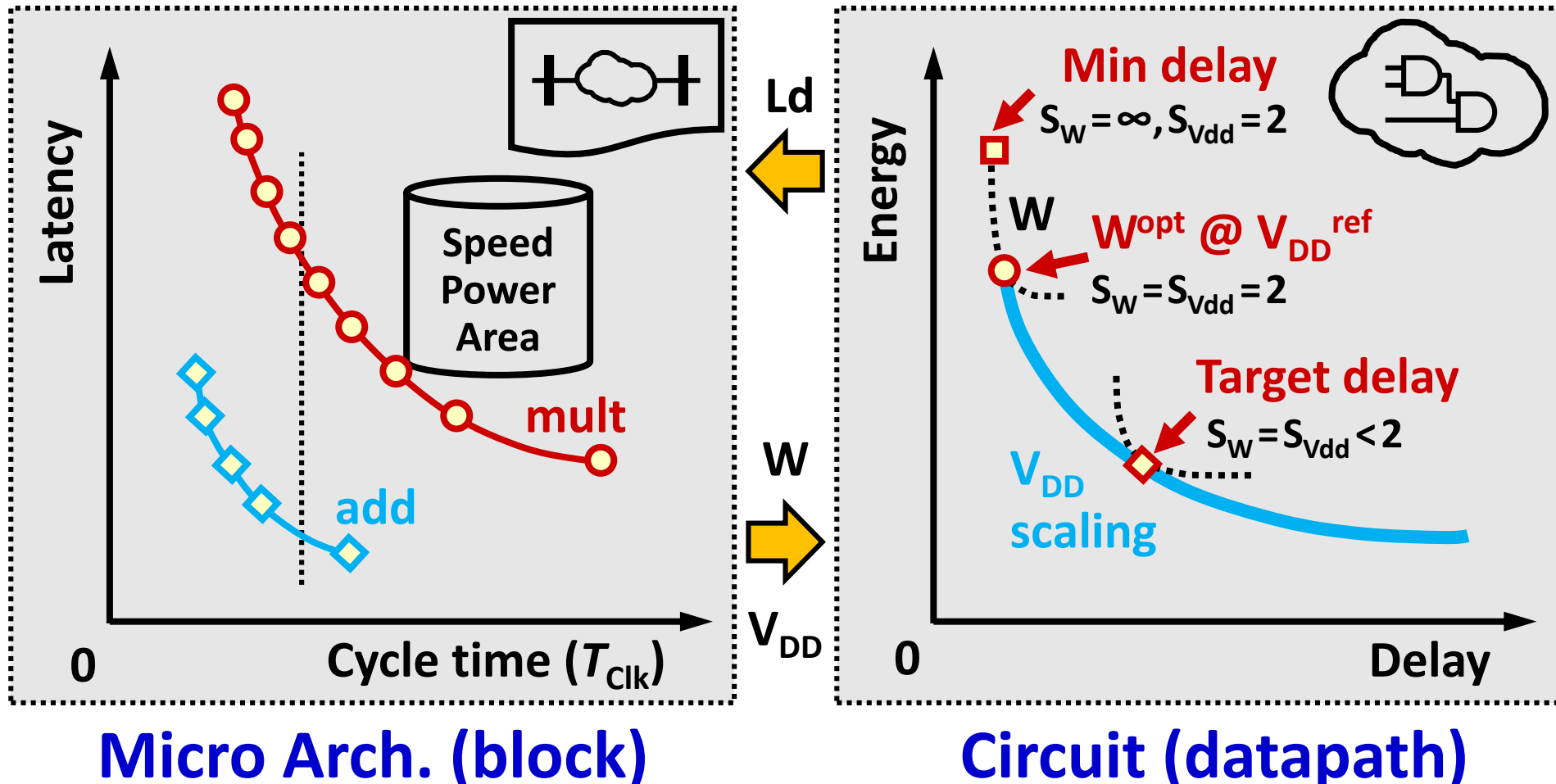
$$A = \frac{1}{5} A_{\text{ref}}$$

$$A = \frac{1}{3} A_{\text{ref}}$$

Low throughput: Time-Mux = Small Area

Putting it All Together

- Balance logic depth (L_d), adjust latency to reach T_{clk}
- Optimize V_{DD} and W of the underlying pipelines



Summary: Design Guidelines

- **For maximum performance**
 - Maximize use of concurrency at the cost of area
- **For given performance**
 - Optimal amount of concurrency for minimum energy
- **For given energy**
 - Least amount of concurrency that meets performance
- **For minimum energy**
 - Solution with minimum overhead
(direct mapping between function and architecture)

System Perspective

- **Optimizations at higher abstraction levels have greater potential impact**
- **While circuit techniques may yield improvements in the 10-50% range**
- **Architecture and algorithm optimizations can reach orders of magnitude power reduction**